











BQ25601D

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# BQ25601D使用 USB 充电器检测实现高输入电压和窄电压直流 (NVDC) 电 源路径管理的 I<sup>2</sup>C 控制型 3A 单节电池充电器

## 1 特性

- 高效 1.5MHz 同步开关模式降压充电器
  - 在 2A 电流 (5V 输入) 下具有 92% 的充电效率
  - 针对 USB 电压输入 (5V) 进行了优化
  - 用于轻负载运行的可选低功耗脉冲频率调制 (PFM) 模式
- 支持 USB On-The-Go (OTG)
  - 具有高达 1.2A 输出的升压转换器
  - 1A 输出下具有 92% 的升压效率
  - 精确的恒定电流 (CC) 限制
  - 高达 500µF 电容负载的软启动
  - 输出短路保护
  - 用于轻负载运行的可选低功耗 PFM 模式
- 单个输入,支持 USB 输入和高压适配器
  - 支持 3.9V 至 13.5V 输入电压范围,绝对最大输入电压额定值为 22V
  - 可编程输入电流限制(100mA 至 3.2A,分辨率 为 100mA),支持 USB 2.0、USB 3.0 标准和 高电压适配器(IINDPM)
  - 通过高达 5.4V 的输入电压限制 (VINDPM) 进行 最大功率跟踪
  - VINDPM 阈值自动跟踪电池电压
  - 自动检测 USB BC1.2、SDP、CDP、DCP 以 及非标准适配器
- 高电池放电效率,电池放电 MOSFET 为 19.5mΩ
- 窄 VDC (NVDC) 电源路径管理
  - 无需电池或深度放电的电池即可瞬时启动
  - 电池充电模式下的理想二极管运行
- BATFET 控制,支持运输模式、唤醒和完全系统复位
- 灵活的自主和 I<sup>2</sup>C 模式,可实现最优系统性能
- 高集成度,包括所有 MOSFET、电流感应和环路补偿
- 17µA 低电池泄漏电流
- 高精度
  - ±0.5% 充电电压调节
  - ±5% 1.5A 充电电流调节

- ±10% 0.9A 输入电流调节
- 可使用 BQ25601D 并借助 WEBENCH® 电源设计器创建定制设计方案

## 2 应用

- 智能手机
- 便携式互联网设备和附件

## 3 说明

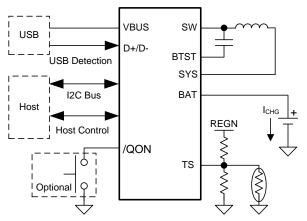
该BQ25601D器件是一款适用于单节锂离子电池和锂聚合物电池的高度集成型 3A 开关模式电池充电管理和系统电源路径管理器件。低阻抗电源路径对开关模式运行效率进行了优化、缩短了电池充电时间并延长了放电阶段的电池使用寿命。具有充电和系统设置的 I<sup>2</sup>C 串行接口使得此器件成为一个真正的灵活解决方案。

## 器件信息<sup>(1)</sup>

器件型号	封装	封装尺寸 (标称值)		
BQ25601D	WQFN (24)	4.00mm × 4.00mm		

(1) 如需了解所有可用封装,请参阅产品说明书末尾的可订购产品 附录。

## 简化应用





## 目录

1	特性 1		9.4 Device Functional Modes	25
2	应用 1		9.5 Protections	29
3			9.6 Programming	30
4	修订历史记录		9.7 Register Maps	34
5	说明(续)3	10	Application and Implementation	46
6	Device Comparison Table		10.1 Application information	46
	-		10.2 Typical Application	47
7	Pin Configuration and Functions5	11	Power Supply Recommendations	
8	Specifications		Layout	
	8.1 Absolute Maximum Ratings		12.1 Layout Guidelines	
	8.2 ESD Ratings		12.2 Layout Example	
	8.3 Recommended Operating Conditions	13	器件和文档支持	
	8.4 Thermal information 8	10	13.1 器件支持	
	8.5 Electrical Characteristics		13.2 文档支持	
	8.6 Timing Requirements		13.3 接收文档更新通知	
	8.7 Typical Characteristics14			
9	Detailed Description 16		13.4 社区资源	
	9.1 Overview 16		13.5 商标	
	9.2 Functional Block Diagram		13.6 静电放电警告	
	9.3 Feature Description		13.7 术语表	
	·	14	机械、封装和可订购信息	57

## 4 修订历史记录

日期	修订版本	说明		
2016 年 4 月	*	初始发行版。		



## 5 说明 (续)

BQ25601D 是一款适用于单节锂离子电池和锂聚合物电池的高度集成型 3A 开关模式电池充电管理和系统电源路径管理器件。该器件 采用 高输入电压快速充电,适用于各类智能手机、平板电脑和便携式设备。其低阻抗电源路径对开关模式运行效率进行了优化、缩短了电池充电时间并延长了放电阶段的电池使用寿命。其输入电压和电流调节可以为电池提供最大的充电功率。该解决方案在系统和电池之间高度集成输入反向阻断 FET(RBFET,Q1)、高侧开关 FET(HSFET,Q2)、低侧开关 FET(LSFET,Q3)以及电池 FET(BATFET、Q4)。它还集成了自举二极管以进行高侧栅极驱动,从而简化系统设计。具有充电和系统设置的 I<sup>2</sup>C 串行接口使得此器件成为一个真正的灵活解决方案。

该器件支持多种输入源,包括标准 USB 主机端口、USB 充电端口以及兼容 USB 的高电压适配器。该器件根据内置 USB 接口设置默认输入电流限值。为了设置默认输入电流限值,器件使用内置 USB 接口或者从系统检测电路(如 USB PHY 器件)中获取结果。该器件符合 USB 2.0 和 USB 3.0 电源规范,具有输入电流和电压调节功能。该器件还具有高达 1.2A 的很定电流限制能力,能够为 VBUS 提供 5.15V 的电压,符合 USB On-the-Go (OTG) 运行功率额定值规范。

电源路径管理将系统电压调节至稍高于电池电压的水平,但是不会下降至 3.5V 最小系统电压(可编程)以下。借助于这个特性,即使在电池电量完全耗尽或者电池被拆除时,系统也能保持运行。当达到输入电流限值或电压限值时,电源路径管理自动将充电电流减少为 0。随着系统负载持续增加,电源路径将使电池放电,直到满足系统电源需求。该补充模式可防止输入源过载。

此器件在无需软件控制情况下启动并完成一个充电周期。它感应电池电压并通过三个阶段为电池充电: 预充电、恒定电流和恒定电压。在充电周期的末尾,当充电电流低于预设限值并且电池电压高于再充电阈值时,充电器自动终止。如果已完全充电的电池降至再充电阈值以下,则充电器自动启动另一个充电周期。

此充电器提供针对电池充电和系统运行情况的多种安全 功能 ,其中包括电池负温度系数热敏电阻监视、充电安全 计时器以及过压和过流保护。当结温超过 110°C(可编程)时,热调节会减小充电电流。STAT 输出报告充电状态 和任何故障状况。其他安全 功能 包括针对充电和升压模式的电池温度感应、热调节和热关断以及输入 UVLO 和过压保护。VBUS\_GD 位指示电源是否正常。当发生故障时,INT 输出会立即通知主机。

该器件还提供用于 BATFET 使能和复位控制的 QON 引脚,以退出低功耗出厂模式或完全系统复位功能。

该器件采用 24 引脚 4mm x 4mm x 0.75mm 薄型 WQFN 封装。

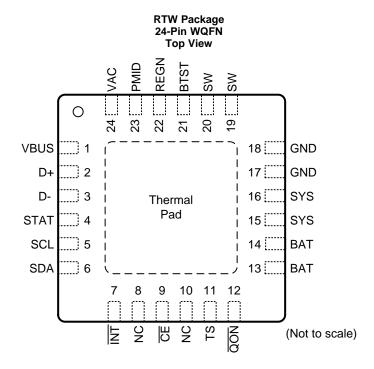
## TEXAS INSTRUMENTS

## 6 Device Comparison Table

	BQ25600(D)	BQ25601(D)	BQ25606
Number of Series Cells	1	1	1
Cell Chemistry	Li-Ion/Li-Polymer	Li-Ion/Li-Polymer	Li-Ion/Li-Polymer
Operation Input Voltage Range (V)	3.9 - 13.5	3.9 - 13.5	3.9 - 13.5
Absolute Max Rating, VBUS (V)	22	22	22
Charge Voltage (V)	3.85 - 4.62	3.85 - 4.62	4.2/4.35/4.4
Charge Current ICHG (A)	3	3	3
Power Path	Yes	Yes	Yes
Discharge Current Rating (A)	6	6	6
I2C / Standalone (I2C Address)	I2C (6BH)	I2C (6BH)	Standalone
USB Detection	BQ25600: PSEL; BQ25600D: D+/D-	BQ25601: PSEL; BQ25601D: D+/D-	D+/D-
BAT Remote Sense	Yes	No	No
Termination Current (A)	60 - 780	60 - 780	5% of ICHG
Precharge Current (A)	60 -780	60 -780	5% of ICHG
Package	WCSP30 - 2x2.4	QFN24 - 4x4	QFN24 - 4x4



## 7 Pin Configuration and Functions



#### **Pin Functions**

ı	Pin	TYPE <sup>(1)</sup>	DESCRIPTION		
NAME	NO.	TIPE	DESCRIPTION		
BAT	13	P	Battery connection point to the positive terminal of the battery pack. The internal BATFET and current sensing is		
14		'	connected between SYS and BAT. Connect a 10 µF close to the BAT pin.		
BTST	21	Р	PWM high side driver positive supply. Internally, the BTST pin is connected to the cathode of the boost-strap diode. Connect the 0.047-μF bootstrap capacitor from SW to BTST.		
CE	9	DI	Charge enable pin. When this pin is driven low, battery charging is enabled.		
CND	17		Cround ping		
GND 18		_	Ground pins.		
ĪNT	7	DO	Open-drain interrupt Output. Connect the INT to a logic rail through 10-k $\Omega$ resistor. The $\overline{\text{INT}}$ pin sends an active low, 256- $\mu$ s pulse to host to report charger device status and fault.		
NC	8	_	No Connect Keen the nine fleet		
NC	10		No Connect. Keep the pins float.		
D-	3	AIO	Negative line of the USB data line pair. D+/D- based USB host/charging port detection. The detection includes data contact detection (DCD), primary and secondary detection in BC1.2 and nonstandard adaptors		
PMID	23	DO	Connected to the drain of the reverse blocking MOSFET (RBFET) and the drain of HSFET. Put 10 $\mu$ F ceramic capacitor on PMID to GND.		
D+	2	AIO	Positive line of the USB data line pair. D+/D- based USB host/charging port detection. The detection includes data contact detection (DCD), primary and secondary detection in BC1.2 and nonstandard adaptors		
QON	12	DI	BATFET enable/reset control input. When BATFET is in ship mode, a logic low of t <sub>SHIPMODE</sub> duration turns on BATFET to exit shipping mode. When VBUS is not pluggeD–in, a logic low of t <sub>QON_RST</sub> (minimum 8 s) duration resets SYS (system power) by turning BATFET off for t <sub>BATFET_RST</sub> (minimum 250 ms) and then re-enable BATFET to provide full system power reset. The pin contains an internal pull-up to maintain default high logic.		
REGN	22	Р	LSFET driver and internal supply output. Internally, REGN is connected to the anode of the boost-strap diode. Connect a 4.7-μF (10-V rating) ceramic capacitor from REGN to GND. The capacitor should be placed close to the IC.		
SCL	5	DI	$I^2C$ interface clock. Connect SCL to the logic rail through a 10-k $\Omega$ resistor.		
SDA	6	DIO	l <sup>2</sup> C interface data. Connect SDA to the logic rail through a 10-kΩ resistor.		

<sup>(1)</sup> AI = Analog input, AO = Analog Output, AIO = Analog input Output, DI = Digital input, DO = Digital Output, DIO = Digital input Output, P = Power



## Pin Functions (continued)

Pin		TYPE(1)	DESCRIPTION	
NAME	NO.	I I I PE'''	DESCRIPTION	
STAT	4	DO	Open-drain charge status output. Connect the STAT pin to a logic rail via 10-kΩ resistor. The STAT pin indicates charger status. Collect a current limit resister and a LED from a rail to this pin. Charge in progress: LOW Charge complete or charger in SLEEP mode: HIGH Charge suspend (fault response): 1-Hz, 50% duty cycle Pulses This pin can be disabled via EN_ICHG_MON[1:0] register bits.	
SW 19 20		. Р	Switching node subject. Connected to subject industry. Connect the 0.047 LF heatstran connector from SW to DTST.	
		P	Switching node output. Connected to output inductor. Connect the 0.047-µF bootstrap capacitor from SW to BTST.	
SYS 15		P	Converter output connection point. The internal current sensing network is connected between SYS and BAT.	
515	16	Connect a 20 µF capacitor close to the SYS pin.		
TS	11	AI	Temperature qualification voltage input to support JEITA profile. Connect a negative temperature coefficient thermistor. Program temperature window with a resistor divider from REGN to TS to GND. Charge suspends when TS pin is out of range. When TS pin is not used, connect a $10\text{-}k\Omega$ resistor from REGN to TS and connect a $10\text{-}k\Omega$ resistor from TS to GND. It is recommended to use a $103\text{AT-}2$ thermistor.	
VAC	24	Al	Charge input voltage sense. This pin must be connected to VBUS pin.	
VBUS	1	Р	Charger input. The internal n-channel reverse block MOSFET (RBFET) is connected between VBUS and PMID pins. Place a 1-uF ceramic capacitor from VBUS to GND close to device.	
Thermal Pad	_	Р	Thermal pad and ground reference. This pad is ground reference for the device and it is also the thermal pad used to conduct heat from the device. This pad should be tied externally to a ground plane through PCB vias under the pad.	



## 8 Specifications

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## 8.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)<sup>(1)</sup>

	and range (amose smormes need)	MIN	MAX	UNIT
Voltage Range (with respect to GND)	VAC, VBUS (converter not switching) <sup>(2)</sup>	-2	22	V
Voltage Range (with respect to GND)	BTST, PMID (converter not switching) (2)	-0.3	22	V
Voltage Range (with respect to GND)	SW	-2	16	V
Voltage Range (with respect to GND)	BTST to SW	-0.3	7	V
Voltage Range (with respect to GND)	D+, D-	-0.3	7	V
Voltage Range (with respect to GND)	REGN, TS, CE, BAT, SYS (converter not switching)	-0.3	7	V
Output Sink Current	STAT		6	mA
Voltage Range (with respect to GND)	SDA, SCL, INT, /QON, STAT	-0.3	7	V
Voltage Range (with respect to GND)	PGND to GND (QFN package only)	-0.3	0.3	V
Output Sink Current	INT		6	mA
Operating junction temperature, T	J	-40	150	°C
Storage temperature, T <sub>stg</sub>		-65	150	°C

<sup>(1)</sup> Stresses beyond those listed under Absolute maximum Ratings may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. All voltage values are with respect to the network ground terminal unless otherwise noted.

(2) VBUS is specified up to 22 V for a maximum of one hour at room temperature

## 8.2 ESD Ratings

			VALUE	UNIT
		Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins <sup>(1)</sup>	±2000	
V <sub>(ESD)</sub>	Electrostatic discharge	Charged device model (CDM), per JEDEC specification JESD22-C101, all pins (2)	±250	V

<sup>(1)</sup> JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

## 8.3 Recommended Operating Conditions

		MIN	NOM MAX	UNIT
V <sub>BUS</sub>	Input voltage	3.9	13.5 <sup>(1)</sup>	V
I <sub>in</sub>	Input current (VBUS)		3.25	Α
I <sub>SWOP</sub>	Output current (SW)		3.25	Α
V <sub>BATOP</sub>	Battery voltage		4.615	V
I <sub>BATOP</sub>	Fast charging current		3.0	Α
I <sub>BATOP</sub>	Discharging current (continuous)		6	Α
T <sub>A</sub>	Operating ambient temperature	-40	85	°C

<sup>(1)</sup> The inherent switching noise voltage spikes should not exceed the absolute maximum voltage rating on either the BTST or SW pins. A tight layout minimizes switching noise.

<sup>(2)</sup> JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

## TEXAS INSTRUMENTS

## 8.4 Thermal information

		BQ25601D	
	THERMAL METRIC <sup>(1)</sup>	RTW (WQFN)	UNIT
		24 PinS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	35.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	22.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	11.9	°C/W
$\Psi_{JT}$	Junction-to-top characterization parameter	0.2	°C/W
$\Psi_{JB}$	Junction-to-board characterization parameter	12	°C/W
$R_{\theta JC(bot)}$	Junction-to-case (bottom) thermal resistance	2.6	°C/W

<sup>(1)</sup> For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report, SPRA953.

## 8.5 Electrical Characteristics

 $V_{VAC\_UVLOZ} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
QUIESCENT CURR	RENTS					
I <sub>BAT</sub>	Battery discharge current (BAT, SW, SYS) in buck mode	$V_{BAT}$ = 4.5 V, $V_{BUS}$ < $V_{AC\text{-}UVLOZ}$ , leakage between BAT and VBUS, $T_{J}$ < 85°C			5	μA
I <sub>BAT</sub>	Battery discharge current (BAT) in buck mode	$V_{BAT}$ = 4.5 V, HIZ Mode and OVPFET_DIS = 1 or No VBUS, I2C disabled, BATFET Disabled. T <sub>J</sub> < 85°C		17	33	μΑ
I <sub>BAT</sub>	Battery discharge current (BAT, SW, SYS)	$V_{\rm BAT}$ = 4.5 V, HIZ Mode and OVPFET_DIS = 1 or No VBUS, I2C Disabled, BATFET Enabled. T <sub>J</sub> < 85°C		58	85	μΑ
I <sub>VBUS_HIZ</sub>	Input supply current (VBUS) in buck mode	V <sub>VBUS</sub> = 5 V, High-Z Mode and OVPFET_DIS = 1, No battery		37	55	μΑ
I <sub>VBUS_HIZ</sub>	Input supply current (VBUS) in buck mode	V <sub>VBUS</sub> = 12 V, High-Z Mode and OVPFET_DIS = 1, No battery		68	93	μΑ
I <sub>VBUS</sub>	Input supply current (VBUS) in buck mode	V <sub>VBUS</sub> = 12 V, V <sub>VBUS</sub> > V <sub>VBAT</sub> , converter not switching		1.5	3	mA
I <sub>VBUS</sub>	Input supply current (VBUS) in buck mode	$V_{VBUS}$ > VUVLO, $V_{VBUS}$ > $V_{VBAT}$ , converter switching, VBAT = 3.8V, ISYS = 0A		3		mA
I <sub>BOOST</sub>	Battery Discharge Current in boost mode	V <sub>BAT</sub> = 4.2 V, boost mode, I <sub>VBUS</sub> = 0 A, converter switching		3		mA
VBUS, VAC AND B	AT PIN POWER-UP				*	
V <sub>BUS_OP</sub>	VBUS operating range	V <sub>VBUS</sub> rising	3.9		13.5	٧
V <sub>VAC_UVLOZ</sub>	VBUS for active I <sup>2</sup> C, no battery Sense VAC pin voltage	V <sub>VAC</sub> rising		3.3	3.6	V
V <sub>VAC_UVLOZ_HYS</sub>	I <sup>2</sup> C active hysteresis	V <sub>AC</sub> falling from above V <sub>VAC_UVLOZ</sub>		300		mV
V <sub>VAC_PRESENT</sub>	One of the conditions to turn on REGN	V <sub>VAC</sub> rising		3.65	3.9	V
V <sub>VAC_PRESENT_HYS</sub>	One of the conditions to turn on REGN	V <sub>VAC</sub> falling		500		mV
V <sub>SLEEP</sub>	Sleep mode falling threshold	$(V_{VAC}-V_{VBAT})$ , $V_{BUSMIN\_FALL} \le V_{BAT}$ $\le V_{REG}$ , VAC falling	15	60	131	mV
V <sub>SLEEPZ</sub>	Sleep mode rising threshold	(V <sub>VAC</sub> -V <sub>VBAT</sub> ), V <sub>BUSMIN_FALL</sub> ≤ V <sub>BAT</sub> ≤ V <sub>REG</sub> , VAC rising	115	220	340	mV
V <sub>VAC_OV_RISE</sub>	VAC 6.5-V Overvoltage rising threshold	VAC rising; OVP (REG06[7:6]) = '01'	6.1	6.4	6.7	V
	•	· ·				



## **Electrical Characteristics (continued)**

 $V_{VAC\_UVLOZ} < V_{VAC} < V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V <sub>VAC_OV_RISE</sub>	VAC 10.5-V Overvoltage rising threshold	VAC rising, OVP (REG06[7:6]) = '10'	10.35	10.9	11.5	V
V <sub>VAC_OV_RISE</sub>	VAC 14-V Overvoltage rising threshold	VAC rising, OVP (REG06[7:6]) = '11'	13.5	14.2	14.85	V
V <sub>VAC_OV_HYS</sub>	VAC 6.5-V Overvoltage hysteresis	VAC falling, OVP (REG06[7:6]) = '01'		320		mV
V <sub>VAC_OV_HYS</sub>	VAC 10.5-V Overvoltage hysteresis	VAC falling, OVP (REG06[7:6]) = '10'		250		mV
V <sub>VAC_OV_HYS</sub>	VAC 14-V Overvoltage hysteresis	VAC falling, OVP (REG06[7:6]) = '11'		300		mV
V <sub>BAT_UVLOZ</sub>	BAT for active I <sup>2</sup> C, no adapter	V <sub>BAT</sub> rising	2.5			V
V <sub>BAT_DPL_FALL</sub>	Battery Depletion Threshold	V <sub>BAT</sub> falling	2.2		2.6	V
V <sub>BAT_DPL_RISE</sub>	Battery Depletion Threshold	V <sub>BAT</sub> rising	2.34		2.86	V
V <sub>BAT_DPL_HYST</sub>	Battery Depletion rising hysteresis	V <sub>BAT</sub> rising		180		mV
V <sub>BUSMIN_FALL</sub>	Bad adapter detection falling threshold	V <sub>BUS</sub> falling	3.75	3.9	4.0	V
V <sub>BUSMIN_HYST</sub>	Bad adapter detection hysteresis			80		mV
I <sub>BADSRC</sub>	Bad adapter detection current source	Sink current from VBUS to GND		30		mA
POWER-PATH						
V <sub>SYS_MIN</sub>	System regulation voltage	V <sub>VBAT</sub> < SYS_MIN[2:0] = 101, BATFET Disabled (REG07[5] = 1)	3.5	3.68		V
V <sub>SYS</sub>	System Regulation Voltage	$I_{SYS} = 0$ A, $V_{VBAT} > V_{SYSMIN}$ , $V_{VBAT} = 4.400$ V, BATFET disabled (REG07[5] = 1)		V <sub>BAT</sub> + 50 mV		V
V <sub>SYS_MAX</sub>	Maximum DC system voltage output	$I_{SYS} = 0 \text{ A}$ , Q4 off, $V_{VBAT} \le 4.400 \text{ V}$ , $V_{VBAT} > V_{SYSMIN} = 3.5 \text{V}$	4.4	4.45	4.48	V
R <sub>ON(RBFET)</sub>	Top reverse blocking MOSFET on-resistance between VBUS and PMID - Q1	-40°C≤ T <sub>A</sub> ≤ 125°C		45		$m\Omega$
R <sub>ON(HSFET)</sub>	Top switching MOSFET on- resistance between PMID and SW - Q2	V <sub>REGN</sub> = 5 V , -40°C≤ T <sub>A</sub> ≤ 125°C		62		mΩ
R <sub>ON(LSFET)</sub>	Bottom switching MOSFET on- resistance between SW and GND - Q3	V <sub>REGN</sub> = 5 V , -40°C≤ T <sub>A</sub> ≤ 125°C		71		mΩ
V <sub>FWD</sub>	BATFET forward voltage in supplement mode			30		mV
R <sub>ON(BAT-SYS)</sub>	SYS-BAT MOSFET on-resistance	QFN package, Measured from BAT to SYS, $V_{BAT} = 4.2V$ , $T_J = 25$ °C		19.5	24	mΩ
R <sub>ON(BAT-SYS)</sub>	SYS-BAT MOSFET on-resistance	QFN package, Measured from BAT to SYS, V <sub>BAT</sub> = 4.2V, T <sub>J</sub> = -40 - 125°C		19.5	30	mΩ
BATTERY CHARG	GER					
V <sub>BATREG_RANGE</sub>	Charge voltage program range		3.847		4.615	V
V <sub>BATREG_STEP</sub>	Charge voltage step			32		mV
		VREG (REG04[7:3]) = 4.20 V (01011), V, -40 ≤ T <sub>J</sub> ≤ 85°C	4.178	4.200	4.220	
V <sub>BATREG</sub>	Charge voltage setting	VREG (REG04[7:3]) = 4.343 V (01111), V, -40 ≤ T <sub>J</sub> ≤ 85°C	4.321	4.343	4.365	V
	1	VREG (REG04[7:3]) = 4.391 V				

## TEXAS INSTRUMENTS

## **Electrical Characteristics (continued)**

 $V_{VAC\_UVLOZ} < V_{VAC\_OV}$  and  $V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
I <sub>CHG_REG_RANGE</sub>	Charge current regulation range		0		3000	mA
I <sub>CHG_REG_STEP</sub>	Charge current regulation step			60		mA
I <sub>CHG_REG</sub>	Charge current regulation setting	$I_{CHG}$ = 240 mA, $V_{VBAT}$ = 3.1V or $V_{VBAT}$ = 3.8 V	0.216	0.24	0.264	Α
I <sub>CHG_REG_ACC</sub>	Charge current regulation accuracy	$I_{CHG}$ = 240 mA, $V_{VBAT}$ = 3.1 V or $V_{VBAT}$ = 3.8 V	-10%		10%	
I <sub>CHG_REG</sub>	Charge current regulation setting	$I_{CHG}$ = 720 mA, $V_{VBAT}$ = 3.1 V or $V_{VBAT}$ = 3.8 V	0.685	0.720	0.761	Α
I <sub>CHG_REG</sub>	Charge current regulation accuracy	$I_{CHG\_REG}$ = 720 mA, $V_{BAT}$ = 3.1 V or $V_{BAT}$ = 3.8 V	-5%		6%	
I <sub>CHG_REG</sub>	Charge current regulation setting	$I_{CHG}$ = 1.38 A, $V_{VBAT}$ = 3.1 V or $V_{VBAT}$ = 3.8 V	1.311	1.380	1.449	Α
I <sub>CHG_REG_ACC</sub>	Charge current regulation accuracy	I <sub>CHG</sub> = 720 mA or I <sub>CHG</sub> = 1.38 A, V <sub>VBAT</sub> = 3.1 V or V <sub>VBAT</sub> = 3.8 V	-5%		5%	
V <sub>BATLOWV_FALL</sub>	Battery LOWV falling threshold	I <sub>CHG</sub> = 240 mA	2.7	2.8	2.9	V
V <sub>BATLOWV_RISE</sub>	Battery LOWV rising threshold	Pre-charge to fast charge	3.0	3.12	3.24	V
I <sub>PRECHG</sub>	Precharge current regulation	IPRECHG[3:0] = '0010' = 180 mA	153	171	189	mA
I <sub>PRECHG_ACC</sub>	Precharge current regulation accuracy	IPRECHG[3:0] = '0010' = 180 mA	-15%		5%	
I <sub>TERM</sub>	Termination current regulation	I <sub>CHG</sub> > 780 mA, ITERM[3:0] = '0010' = 180 mA, V <sub>VBAT</sub> = 4.208 V	150	180	216	mA
I <sub>TERM_ACC</sub>	Termination current regulation accuracy	I <sub>CHG</sub> > 780 mA, , ITERM[3:0] = '0010' = 180 mA, V <sub>VBAT</sub> = 4.208 V	-16.7%		20%	
I <sub>TERM</sub>	Termination current regulation	I <sub>CHG</sub> ≤ 780 mA, , ITERM[3:0] = '0010' = 180 mA	162	180	192	mA
I <sub>TERM_ACC</sub>	Termination current regulation accuracy	I <sub>CHG</sub> ≤ 780 mA, , ITERM[3:0] = '0010' = 180 mA	-10%		10%	
I <sub>TERM</sub>	Termination current regulation	I <sub>CHG</sub> = 600 mA, ITERM[3:0] = '0000' = 60 mA, V <sub>VBAT</sub> = 4.208 V	45	60	85	mA
I <sub>TERM_ACC</sub>	Termination current regulation accuracy	I <sub>CHG</sub> = 600 mA, ITERM[3:0] = '0000' = 60 mA, V <sub>VBAT</sub> = 4.208 V	-25%		42%	
V <sub>SHORT</sub>	Battery short voltage	V <sub>VBAT</sub> falling	1.85	2	2.15	V
V <sub>SHORTZ</sub>	Battery short voltage	V <sub>VBAT</sub> rising	2.15	2.25	2.35	V
I <sub>SHORT</sub>	Battery short current	V <sub>VBAT</sub> < V <sub>SHORTZ</sub>	70	90	110	mA
$V_{RECHG}$	Recharge Threshold below V <sub>BAT_REG</sub>	V <sub>BAT</sub> falling, REG04[0] = 0	90	120	150	mV
$V_{RECHG}$	Recharge Threshold below V <sub>BAT_REG</sub>	V <sub>BAT</sub> falling, REG04[0] = 1	200	230	265	mV
I <sub>SYSLOAD</sub>	System discharge load current	V <sub>SYS</sub> = 4.2 V		30		mA
INPUT VOLTAGE	AND CURRENT REGULATION					
$V_{\text{INDPM}}$	Input voltage regulation limit	V <sub>INDPM</sub> (REG06[3:0] = 0000) = 3.9 V	3.78	3.95	4.1	V
$V_{\text{INDPM\_ACC}}$	Input voltage regulation accuracy		-3%		5%	
$V_{INDPM}$	Input voltage regulation limit	V <sub>INDPM</sub> (REG06[3:0] = 0110) = 4.4 V	4.268	4.4	4.532	V
$V_{INDPM\_ACC}$	Input voltage regulation accuracy		-3%		3%	
V <sub>DPM_VBAT</sub>	Input voltage regulation limit tracking VBAT	VINDPM = 3.9V, VDPM_VBAT_TRACK = 300mV, VBAT = 4.0V	4.171	4.3	4.43	V
V <sub>DPM_VBAT_ACC</sub>	Input voltage regulation accuracy tracking VBAT		-3%		3%	



## **Electrical Characteristics (continued)**

 $V_{VAC\_UVLOZ} < V_{VAC\_OV}$  and  $V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
		$V_{VBUS} = 5$ V, current pulled from SW, $I_{INDPM}$ (REG[4:0] = 00100) = 500 mA, $-40 \le T_J \le 85^{\circ}C$	450		500	mA
I <sub>INDPM</sub>	USB input current regulation limit	$V_{VBUS} = 5$ V, current pulled from SW, IINDPM (REG[4:0] = 01000) = 900 mA, $-40 \le T_J \le 85^{\circ}$ C	750		900	mA
		$V_{VBUS} = 5$ V, current pulled from SW, IINDPM (REG[4:0] = 01110) = 1.5 A, $-40 \le T_J \le 85^{\circ}C$	1.3		1.5	Α
I <sub>IN_START</sub>	Input current limit during system start-up sequence			200		mA
BAT PIN OVERV	OLTAGE PROTECTION					
V <sub>BATOVP_RISE</sub>	Battery overvoltage threshold	$V_{\text{BAT}}$ rising, as percentage of $V_{\text{BAT\_REG}}$	103%	104%	105%	
V <sub>BATOVP_FALL</sub>	Battery overvoltage threshold	$V_{\text{BAT}}$ falling, as percentage of $V_{\text{BAT\_REG}}$	101%	102%	103%	
THERMAL REGU	LATION AND THERMAL SHUTDOW	N				
T <sub>JUNCTION_REG</sub>	Junction Temperature Regulation Threshold	Temperature Increasing, TREG (REG05[1] = 1) = 110°C		110		°C
T <sub>JUNCTION_REG</sub>	Junction Temperature Regulation Threshold	Temperature Increasing, TREG (REG05[1] = 0) = 90°C		90		°C
T <sub>SHUT</sub>	Thermal Shutdown Rising Temperature	Temperature Increasing		160		°C
T <sub>SHUT_HYST</sub>	Thermal Shutdown Hysteresis			30		°C
JEITA Thermisto	r Comparator (BUCK MODE)					
V <sub>T1</sub>	T1 (0°C) threshold, Charge suspended T1 below this temperature.	Charger suspends charge. As Percentage to V <sub>REGN</sub>	72.4%	73.3%	74.2%	
V <sub>T1</sub>	Falling	As Percentage to V <sub>REGN</sub>	69%	71.5%	74%	
V <sub>T2</sub>	T2 (10°C) threshold, Charge back to $I_{CHG}/2$ and 4.2 V below this temperature	As percentage of V <sub>REGN</sub>	67.2%	68%	69%	
$V_{T2}$	Falling	As Percentage to V <sub>REGN</sub>	66%	66.8%	67.7%	
V <sub>T3</sub>	T3 (45°C) threshold, charge back to ICHG and 4.05V above this temperature.	Charger suspends charge. As Percentage to V <sub>REGN</sub>	43.8%	44.7%	45.8%	
V <sub>T3</sub>	Falling	As Percentage to V <sub>REGN</sub>	45.1%	45.7%	46.3%	
V <sub>T5</sub>	T5 (60°C) threshold, charge suspended above this temperature.	As Percentage to V <sub>REGN</sub>	33.7%	34.2%	35.1%	
V <sub>T5</sub>	Falling	As Percentage to V <sub>REGN</sub>	34.5%	35.3%	36.3%	
COLD OR HOT T	HERMISTER COMPARATOR (BOOS	T MODE)			<del></del>	
V <sub>BCOLD</sub>	Cold Temperature Threshold, TS pin Voltage Rising Threshold	As Percentage to $V_{REGN}$ (Approx20°C w/ 103AT), $T_{J} = -20$ °C - 125°C	79.5%	80%	80.5%	
V <sub>BCOLD</sub>	Falling	T <sub>J</sub> = -20°C - 125°C	78.3%	79%	79.7%	
V <sub>BHOT</sub>	Hot Temperature Threshold, TS pin Voltage falling Threshold	As Percentage to V <sub>REGN</sub> (Approx. 60°C w/ 103AT), T <sub>J</sub> = -20°C - 125°C	30.2%	31.2%	32.2%	
V <sub>BHOT</sub>	Rising	T <sub>J</sub> = -20°C - 125°C	33.8%	34.4%	34.9%	

## TEXAS INSTRUMENTS

## **Electrical Characteristics (continued)**

 $V_{VAC\_UVLOZ} < V_{VAC\_OV}$  and  $V_{VAC\_OV}$  and  $V_{VAC} > V_{BAT} + V_{SLEEP}$ ,  $T_J = -40^{\circ}C$  to 125°C and  $T_J = 25^{\circ}C$  for typical values (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
CHARGE OVERO	CURRENT COMPARATOR (CYCLE-E	BY-CYCLE)				
I <sub>HSFET_OCP</sub>	HSFET cycle-by-cycle over- current threshold		5.2		8.0	Α
I <sub>BATFET_OCP</sub>	System over load threshold		6.0			Α
PWM						
£	DIAMA quitabing fraguency	Oscillator frequency, buck mode	1320	1500	1680	kHz
f <sub>SW</sub>	PWM switching frequency	Oscillator frequency, boost mode	1150	1412	1660	kHz
D <sub>MAX</sub>	Maximum PWM duty cycle <sup>(1)</sup>			97%		
BOOST MODE O	PERATION					
V <sub>OTG_REG</sub>	Boost mode regulation voltage	V <sub>VBAT</sub> = 3.8 V, I <sub>(PMID)</sub> = 0 A, BOOSTV[1:0] = '10' = 5.15 V	4.97	5.126	5.280	V
V <sub>OTG_REG_ACC</sub>	Boost mode regulation voltage accuracy	V <sub>VBAT</sub> = 3.8 V, I <sub>(PMID)</sub> = 0 A, BOOSTV[1:0] = '10' = 5.15 V	-3%		3%	
V <sub>BATLOWV_</sub> OTG		V <sub>VBAT</sub> falling, MIN_V <sub>BAT</sub> _SEL (REG01[0]) = 0	2.6	2.8	2.93	V
	Battery voltage exiting boost mode	V <sub>VBAT</sub> rising, MIN_V <sub>BAT</sub> _SEL (REG01[0]) = 0	2.9	3.0	3.15	V
		V <sub>VBAT</sub> falling, MIN_V <sub>BAT</sub> _SEL (REG01[0]) = 1	2.38	2.5	2.6	V
		V <sub>VBAT</sub> rising, MIN_V <sub>BAT</sub> _SEL (REG01[0]) = 1	2.7	2.8	2.93	V
I <sub>OTG</sub>	OTG mode output current	BOOST_LIM (REG02[7]) = 1	1.2	1.4	1.6	Α
I <sub>OTG_OCP_ACC</sub>	Boost mode RBFET over-current protection accuracy	BOOST_LIM = 0.5 A (REG02[7] = 0)	0.5		0.722	Α
V <sub>OTG_OVP</sub>	OTG overvoltage threshold	Rising threshold	5.55	5.8	6.15	V
REGN LDO	,				,	
V <sub>REGN</sub>	REGN LDO output voltage	$V_{VBUS} = 9V$ , $I_{REGN} = 40$ mA	5.6	6	6.55	V
V <sub>REGN</sub>	REGN LDO output voltage	$V_{VBUS} = 5V$ , $I_{REGN} = 20$ mA	4.6	4.7	4.8	V
	HARACTERISTICS (CE, INT, STAT)					
V <sub>ILO</sub>	Input low threshold				0.4	V
V <sub>IH</sub>	Input high threshold		1.3			V
I <sub>BIAS</sub>	High-level leakage current	Pull up rail 1.8 V			1	μA
I2C Interface (SC		·				
V <sub>IH</sub>	Input high threshold level	Pull up rail 1.8 V	1.3			V
V <sub>IL</sub>	Input t low threshold level	Pull up rail 1.8 V			0.4	V
V <sub>OL</sub>	Output low threshold level	Sink current = 5 mA,			0.4	V

<sup>(1)</sup> Specified by design. Not production tested.

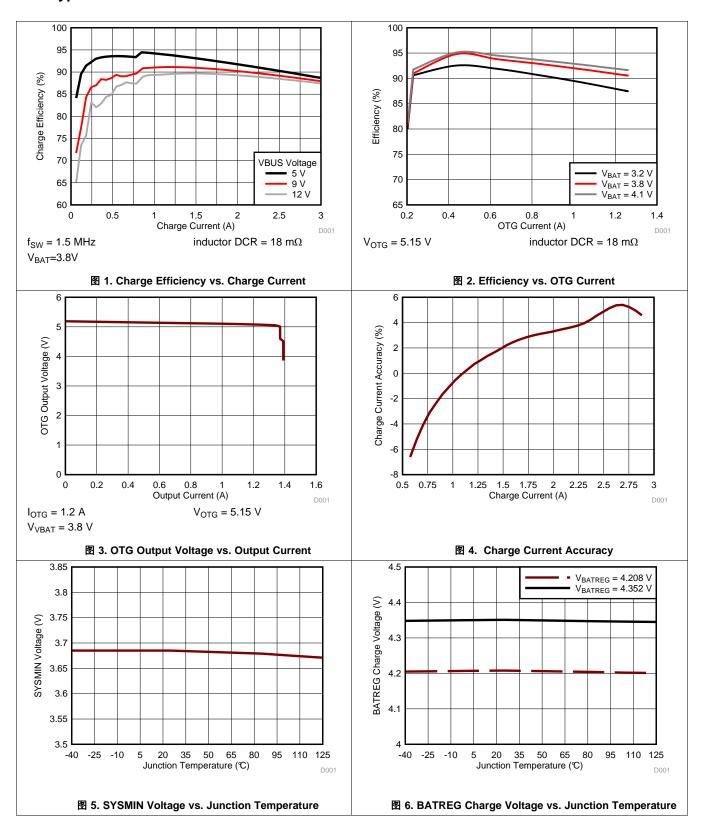


8.6 Timing Requirements

			MIN	NOM	MAX	UNIT
VBUS/BAT P	OWER UP					
t <sub>ACOV</sub>	VAC OVP reaction time	VAC rising above ACOV threshold to turn off Q2		200		ns
t <sub>BADSRC</sub>	Bad adapter detection duration			30		ms
BATTERY CH	IARGER					
t <sub>TERM_DGL</sub>	Deglitch time for charge termination			250		ms
t <sub>RECHG_DGL</sub>	Deglitch time for recharge			250		ms
tsysovld_dgl	System over-current deglitch time to turn off Q4			100		μs
t <sub>BATOVP</sub>	Battery over-voltage deglitch time to disable charge			1		μs
t <sub>SAFETY</sub>	Typical Charge Safety Timer Range	CHG_TIMER = 1	8	10	12	hr
t <sub>TOP_OFF</sub>	Typical Top-Off Timer Range	TOP_OFF_TIMER[1:0] = 10 (30 min)	24	30	36	min
QON TIMING						
t <sub>SHIPMODE</sub>	/QON low time to turn on BATFET and exit ship mode	-10°C ≤ T <sub>J</sub> ≤ 60°C	0.9		1.3	s
t <sub>QON_RST_2</sub>	QON low time to reset BATFET	-10°C ≤ T <sub>J</sub> ≤ 60°C	8		12	s
t <sub>BATFET_RST</sub>	BATFET off time during full system reset	-10°C ≤ T <sub>J</sub> ≤ 60°C	250		400	ms
t <sub>SM_DLY</sub>	Enter ship mode delay	-10°C ≤ T <sub>J</sub> ≤ 60°C	10		15	s
DIGITAL CLO	OCK AND WATCHDOG TIMER					
t <sub>WDT</sub>	REG05[4]=1	REGN LDO disabled		40		s
f <sub>LPDIG</sub>	Digital Low Power Clock	REGN LDO disabled		30		kHz
f <sub>DIG</sub>	Digital Clock	REGN LDO enabled		500		kHz
f <sub>SCL</sub>	SCL clock frequency				400	kHz

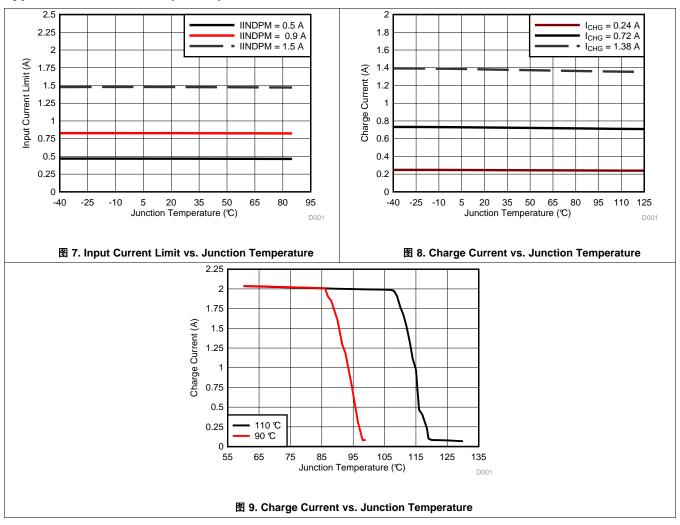
## TEXAS INSTRUMENTS

## 8.7 Typical Characteristics





## Typical Characteristics (接下页)



## TEXAS INSTRUMENTS

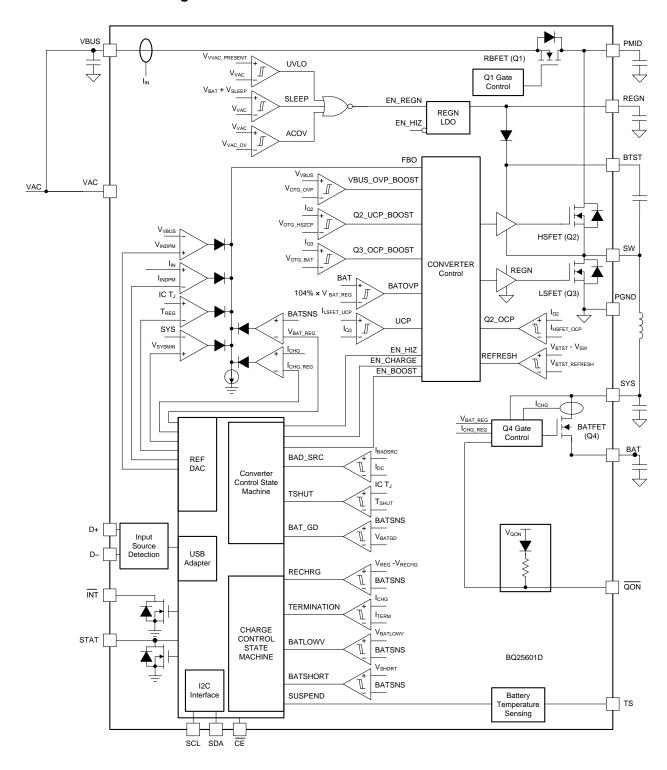
## 9 Detailed Description

## 9.1 Overview

The BQ25601D device is a highly integrated 3.0-A switch-mode battery charger for single cell Li-lon and Lipolymer battery. It includes the input reverse-blocking FET (RBFET, Q1), high-side switching FET (HSFET, Q2), low-side switching FET (LSFET, Q3), and battery FET (BATFET, Q4), and bootstrap diode for the high-side gate drive.



## 9.2 Functional Block Diagram



## TEXAS INSTRUMENTS

### 9.3 Feature Description

## 9.3.1 Power-On-Reset (POR)

The device powers internal bias circuits from the higher voltage of VBUS and BAT. When VBUS rises above  $V_{VBUS\_UVLOZ}$  or BAT rises above  $V_{BAT\_UVLOZ}$ , the sleep comparator, battery depletion comparator and BATFET driver are active. I<sup>2</sup>C interface is ready for communication and all the registers are reset to default value. The host can access all the registers after POR.

### 9.3.2 Device Power Up from Battery without Input Source

If only battery is present and the voltage is above depletion threshold (V<sub>BAT\_DPL\_RISE)</sub>, the BATFET turns on and connects battery to system. The REGN stays off to minimize the quiescent current. The low RDSON of BATFET and the low quiescent current on BAT minimize the conduction loss and maximize the battery run time.

The device always monitors the discharge current through BATFET (Supplement Mode). When the system is overloaded or shorted ( $I_{BAT} > I_{BATFET\_OCP}$ ), the device turns off BATFET immediately and set BATFET\_DIS bit to indicate BATFET is disabled until the input source plugs in again or one of the methods described in BATFET Enable (Exit Shipping Mode) is applied to re-enable BATFET.

## 9.3.3 Power Up from Input Source

When an input source is plugged in, the device checks the input source voltage to turn on REGN LDO and all the bias circuits. It detects and sets the input current limit before the buck converter is started. The power up sequence from input source is as listed:

- 1. Power Up REGN LDO
- 2. Poor Source Qualification
- 3. Input Source Type Detection is based on D+/D- to set default input current limit (IINDPM) register or input source type.
- 4. Input Voltage Limit Threshold Setting (VINDPM threshold)
- 5. Converter Power-up

## 9.3.3.1 Power Up REGN Regulation

The REGN LDO supplies internal bias circuits as well as the HSFET and LSFET gate drive. The REGN also provides bias rail to TS external resistors. The pull-up rail of STAT can be connected to REGN as well. The REGN is enabled when all the below conditions are valid:

- V<sub>VAC</sub> above V<sub>VAC</sub> PRESENT
- V<sub>VAC</sub> above V<sub>BAT</sub> + V<sub>SLEEPZ</sub> in buck mode or VBUS below V<sub>BAT</sub> + V<sub>SLEEP</sub> in boost mode
- After 220-ms delay is completed

If any one of the above conditions is not valid, the device is in high impedance mode (HIZ) with REGN LDO off. The device draws less than IVBUS\_HIZ from VBUS during HIZ state. The battery powers up the system when the device is in HIZ.

#### 9.3.3.2 Poor Source Qualification

After REGN LDO powers up, the device confirms the current capability of the input source. The input source must meet both of the following requirements in order to start the buck converter.

- VBUS voltage below V<sub>VAC OV</sub>
- VBUS voltage above V<sub>VBUSMIN</sub> when pulling I<sub>BADSRC</sub> (typical 30 mA)

Once the input source passes all the conditions above, the status register bit VBUS\_GD is set high and the INT pin is pulsed to signal to the host. If the device fails the poor source detection, it repeats poor source qualification every 2 seconds.

#### 9.3.3.3 Input Source Type Detection

After the VBUS\_GD bit is set and REGN LDO is powered, the device runs input source detection through D+/D-lines. The BQ25601D follows the USB Battery Charging Specification 1.2 (BC1.2) to detect input source (SDP/DCP) and non-standard adapter through USB D+/D-lines.



## Feature Description (接下页)

After input source type detection is completed, an INT pulse is asserted to the host. in addition, the following registers and pin are changed:

- 1. Input Current Limit (IINDPM) register is changed to set current limit
- 2. PG STAT bit is set
- 3. VBUS STAT bit is updated to indicate USB or other input source

The host can over-write IINDPM register to change the input current limit if needed. The charger input current is always limited by the IINDPM register.

#### 9.3.3.3.1 D+/D- Detection Sets Input Current Limit in BQ25601D

The BQ25601D contains a D+/D- based input source detection to set the input current limit at VBUS plug-in. The D+/D- detection includes standard USB BC1.2 and non-standard adapter. When input source is plugged in, the device starts standard USB BC1.2 detections. The USB BC1.2 is capable to identify Standard Downstream Port (SDP) and Dedicated Charging Port (DCP). When the Data Contact Detection (DCD) timer expires, the non-standard adapter detection is applied to set the input current limit. The non-standard detection is used to distinguish vendor specific adapters (Apple and Samsung) based on their unique dividers on the D+/D- pins. If an adapter is detected as DCP, the input current limit is set at 2.4 A. If an adapter is detected as unknown, the input current limit is set at 0.5 A.

NON-STANDARD ADAPTER	D+ THRESHOLD D- THRESHOLD		INPUT CURRENT LIMIT (A)
Divider 1	V <sub>D+</sub> within V <sub>2P7_VTH</sub>	V <sub>D</sub> within V <sub>2P0_VTH</sub>	2.1
Divider 2	V <sub>D+</sub> within V <sub>1P2_VTH</sub>	V <sub>D</sub> within V <sub>1P2_VTH</sub>	2
Divider 3	V <sub>D+</sub> within V <sub>2P0_VTH</sub>	V <sub>D</sub> within V <sub>2P7_VTH</sub>	1
Divider 4	V <sub>D+</sub> within V <sub>2P7_VTH</sub>	V <sub>D</sub> within V <sub>2P7_VTH</sub>	2.4

表 1. Non-Standard Adapter Detection

### 表 2. Input Current Limit Setting from D+/D- Detection

D+/D- DETECTION	INPUT CURRENT LIMIT (IINLIM)
USB SDP (USB500)	500 mA
USB DCP	2.4 A
Divider 3	1 A
Divider 1	2.1 A
Divider 4	2.4 A
Divider 2	2 A
Unknown 5-V Adapter	

### 9.3.3.4 Input Voltage Limit Threshold Setting (VINDPM Threshold)

The device supports wide range of input voltage limit (3.9 V - 5.4V) for USBThe device's VINDPM is set at 4.5V. The device supports dynamic VINDPM trackingsettings which tracks the battery voltage. This function can be enabled via the VDPM\_BAT\_TRACK[1:0] register bits. When enabled, the actual input voltage limit will be the higher of the VINDPM register and VBAT + VDPM\_BAT\_TRACK offset.

### 9.3.3.5 Converter Power-Up

After the input current limit is set, the converter is enabled and the HSFET and LSFET start switching. If battery charging is disabled, BATFET turns off. Otherwise, BATFET stays on to charge the battery.

The device provides soft-start when system rail is ramped up. When the system rail is below 2.2 V, the input current is limited to is to the lower of 200 mA or IINDPM register setting. After the system rises above 2.2 V, the device limits input current to the value set by IINDPM register.

As a battery charger, the device deploys a highly efficient 1.5 MHz step-down switching regulator. The fixed frequency oscillator keeps tight control of the switching frequency under all conditions of input voltage, battery voltage, charge current and temperature, simplifying output filter design.



The device switches to PFM control at light load or when battery is below minimum system voltage setting or charging is disabled. The PFM\_DIS bit can be used to prevent PFM operation in either buck or boost configuration.

## 9.3.4 Boost Mode Operation From Battery

The device supports boost converter operation to deliver power from the battery to other portable devices through USB port. The boost mode output current rating meets the USB On-The-Go 500 mA output requirement. The maximum output current is up to 1.2 A. The boost operation can be enabled if the conditions are valid:

- 1. BAT above V<sub>OTG BAT</sub>
- 2. VBUS less than BAT+V<sub>SLEEP</sub> (in sleep mode)
- 3. Boost mode operation is enabled (OTG\_CONFIG bit = 1)
- 4. Voltage at TS (thermistor) pin is within acceptable range ( $V_{BHOT} < V_{TS} < V_{BCOLD}$ )
- 5. After 30-ms delay from boost mode enable

During boost mode, the status register VBUS\_STAT bits is set to 111, the VBUS output is 5.15 V and the output current can reach up to 1.2 A, selected through  $I^2C$  (BOOST\_LIM bit). The boost output is maintained when BAT is above  $V_{OTG\_BAT}$  threshold.

When OTG is enabled, the device starts up with PFM and later transits to PWM to minimize the overshoot. The PFM\_DIS bit can be used to prevent PFM operation in either buck or boost configuration.

## 9.3.5 Host Mode and Standalone Power Management

#### 9.3.5.1 Host Mode and Default Mode in BQ25601D

The BQ25601D is a host controlled charger, but it can operate in default mode without host management. in default mode, the device can be used as an autonomous charger with no host or while host is in sleep mode. When the charger is in default mode, WATCHDOG\_FAULT bit is HIGH. When the charger is in host mode, WATCHDOG\_FAULT bit is LOW.

After power-on-reset, the device starts in default mode with watchdog timer expired, or default mode. All the registers are in the default settings.

in default mode, the device keeps charging the battery with default 10-hour fast charging safety timer. At the end of the 10-hour, the charging is stopped and the buck converter continues to operate to supply system load.

Writing a 1 to the WD\_RST bit transitions the charger from default mode to host mode. All the device parameters can be programmed by the host. To keep the device in host mode, the host has to reset the watchdog timer by writing 1 to WD\_RST bit before the watchdog timer expires (WATCHDOG\_FAULT bit is set), or disable watchdog timer by setting WATCHDOG bits = 00.

When the watchdog timer expires (WATCHDOG\_FAULT bit = 1), the device returns to default mode and all registers are reset to default values except IINDPM, VINDPM, BATFET\_RST\_EN, BATFET\_DLY, and BATFET DIS bits.



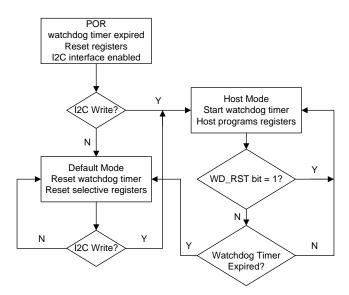


图 10. Watchdog Timer Flow Chart

### 9.3.6 Power Path Management

The device accommodates a wide range of input sources from USB, wall adapter, to car charger. The device provides automatic power path selection to supply the system (SYS) from input source (VBUS), battery (BAT), or both.

### 9.3.7 Battery Charging Management

The device charges 1-cell Li-lon battery with up to 3.0-A charge current for high capacity tablet battery. The 19.5- $m\Omega$  BATFET improves charging efficiency and minimize the voltage drop during discharging.

## 9.3.7.1 Autonomous Charging Cycle

With battery charging is enabled (CHG\_CONFIG bit = 1 and  $\overline{CE}$  pin is LOW), the device autonomously completes a charging cycle without host involvement. The device default charging parameters are listed in  $\frac{1}{2}$   $\frac{1}{2}$ . The host can always control the charging operations and optimize the charging parameters by writing to the corresponding registers through  $1^2$ C.

DEFAULT MODE	BQ25601D
Charging voltage	4.208V
Charging current	2.048 A
Pre-charge current	180 mA
Termination current	180 mA
Temperature profile	JEITA
Safety timer	10 hours

表 3. Charging Parameter Default Setting

A new charge cycle starts when the following conditions are valid:

- Converter starts
- Battery charging is enabled (CHG\_CONFIG bit = 1 and I<sub>CHG</sub> register is not 0 mA and CE is low)
- · No thermistor fault on TS
- No safety timer fault
- BATFET is not forced to turn off (BATFET\_DIS bit = 0)



The charger device automatically terminates the charging cycle when the charging current is below termination threshold, battery voltage is above recharge threshold, and device not is in DPM mode or thermal regulation. When a fully charged battery is discharged below recharge threshold (selectable through VRECHG bit), the device automatically starts a new charging cycle. After the charge is done, toggle  $\overline{\text{CE}}$  pin or CHG\_CONFIG bit can initiate a new charging cycle.

The STAT output indicates the charging status: charging (LOW), charging complete or charge disable (HIGH) or charging fault (Blinking). The STAT output can be disabled by setting EN\_ICHG\_MON bits = 11. in addition, the status register (CHRG\_STAT) indicates the different charging phases: 00-charging disable, 01-precharge, 10-fast charge (constant current) and constant voltage mode, 11-charging done. Once a charging cycle is completed, an INT is asserted to notify the host.

### 9.3.7.2 Battery Charging Profile

The device charges the battery in five phases: battery short, preconditioning, constant current, constant voltage and top-off trickle charging (optional). At the beginning of a charging cycle, the device checks the battery voltage and regulates current and voltage accordingly.

V <sub>BAT</sub>	CHARGING CURRENT	REGISTER DEFAULT SETTING	CHRG_STAT
< 2.2 V	I <sub>SHORT</sub>	100 mA	01
2.2 V to 3 V	I <sub>PRECHG</sub>	180 mA	01
> 3 V	I <sub>CHG</sub>	2.048 A	10

表 4. Charging Current Setting

If the charger device is in DPM regulation or thermal regulation during charging, the actual charging current will be less than the programmed value. in this case, termination is temporarily disabled and the charging safety timer is counted at half the clock rate.

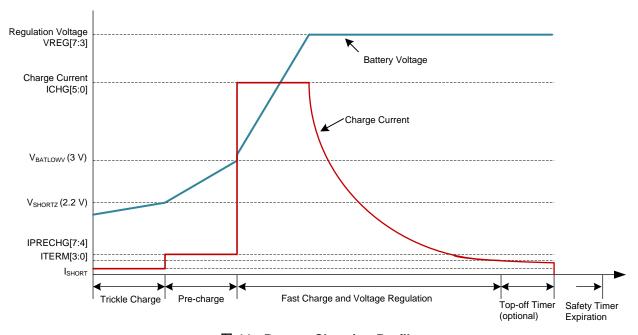


图 11. Battery Charging Profile

## 9.3.7.3 Charging Termination

The device terminates a charge cycle when the battery voltage is above recharge threshold, and the current is below termination current. After the charging cycle is completed, the BATFET turns off. The converter keeps running to power the system, and BATFET can turn on again to engage *Supplement Mode*.



When termination occurs, the status register CHRG\_STAT is set to 11, and an INT pulse is asserted to the host. Termination is temporarily disabled when the charger device is in input current, voltage or thermal regulation. Termination can be disabled by writing 0 to EN TERM bit prior to charge termination.

At low termination currents (25 mA-50 mA), due to the comparator offset, the actual termination current may be 10 mA-20 mA higher than the termination target. in order to compensate for comparator offset, a programmable top-off timer can be applied after termination is detected. The termination timer will follow safety timer constraints, such that if safety timer is suspended, so will the termination timer. Similarly, if safety timer is doubled, so will the termination timer. TOPOFF\_ACTIVE bit reports whether the top off timer is active or not. The host can read CHRG\_STAT and TOPOFF\_ACTIVE to find out the termination status.

Top off timer gets reset at one of the following conditions:

- 1. Charge disable to enable
- 2. Termination status low to high
- 3. REG\_RST register bit is set

The top-off timer settings are read in once termination is detected by the charger. Programming a top-off timer value after termination will have no effect unless a recharge cycle is initiated. An INT is asserted to the host when entering top-off timer segment as well as when top-off timer expires.

#### 9.3.7.4 Thermistor Qualification

The charger device provides a single thermistor input for battery temperature monitor.

### 9.3.7.5 JEITA Guideline Compliance During Charging Mode

To improve the safety of charging Li-ion batteries, JEITA guideline was released on April 20, 2007. The guideline emphasized the importance of avoiding a high charge current and high charge voltage at certain low and high temperature ranges.

To initiate a charge cycle, the voltage on TS pin must be within the VT1 to VT5 thresholds. If TS voltage exceeds the T1-T5 range, the controller suspends charging and waits until the battery temperature is within the T1 to T5 range.

At cool temperature (T1-T2), JEITA recommends the charge current to be reduced to half of the charge current or lower. At warm temperature (T3-T5), JEITA recommends charge voltage less than 4.1 V.

The charger provides flexible voltage/current settings beyond the JEITA requirement. The voltage setting at warm temperature (T3-T5) can be VREG or 4.1V (configured by JEITA\_VSET). The current setting at cool temperature (T1-T2) can be further reduced to 20% of fast charge current (JEITA\_ISET).

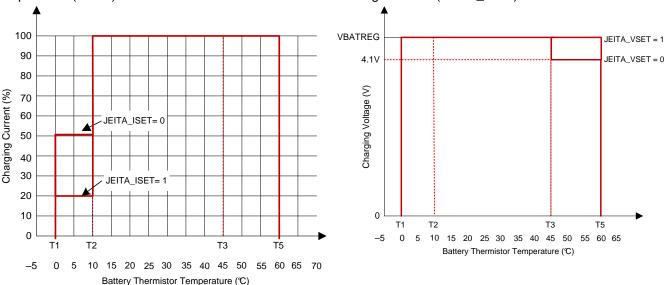


图 12. JEITA Profile: Charging Current

图 13. JEITA Profile: Charging Voltage

TEXAS INSTRUMENTS

公式 1 through 公式 2 describe updates to the resistor bias network.

$$RT2 = \frac{V_{REGN} \times RTH_{COLD} \times RTH_{HOT} \times \left(\frac{1}{VT1} - \frac{1}{VT5}\right)}{RTH_{HOT} \times \left(\frac{V_{REGN}}{VT5} - 1\right) - RTH_{COLD} \times \left(\frac{V_{REGN}}{VT1} - 1\right)}$$

$$RT1 = \frac{\left(\left(\frac{V_{REGN}}{VT1}\right) - 1\right)}{\left(\frac{1}{RT2}\right) + \left(\frac{1}{RTH_{COLD}}\right)}$$
(1)

Select 0°C to 60°C range for Li-ion or Li-polymer battery:

- RTH<sub>COLD</sub> = 27.28 K $\Omega$
- RTH<sub>HOT</sub> = 3.02 KΩ
- RT1 = 5.23 KΩ
- RT2 = 30.9 KΩ

### 9.3.7.6 Boost Mode Thermistor Monitor during Battery Discharge Mode

For battery protection during boost mode, the device monitors the battery temperature to be within the VBCOLD to VBHOTthresholds. When temperature is outside of the temperature thresholds, the boost mode is suspended. In additional, VBUS\_STAT bits are set to 000 and NTC\_FAULT is reported. Once temperature returns within thresholds, the boost mode is recovered and NTC\_FAULT is cleared.

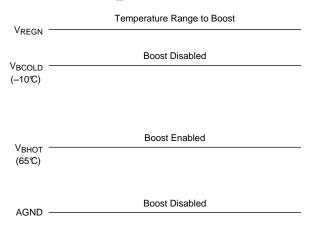


图 14. TS Pin Thermistor Sense Threshold in Boost Mode

#### 9.3.7.7 Charging Safety Timer

The device has built-in safety timer to prevent extended charging cycle due to abnormal battery conditions. The safety timer is 2 hours when the battery is below  $V_{BATLOWV}$  threshold and 10 hours when the battery is higher than  $V_{BATLOWV}$  threshold.

The user can program fast charge safety timer through I<sup>2</sup>C (CHG\_TIMER bits). When safety timer expires, the fault register CHRG\_FAULT bits are set to 11 and an INT is asserted to the host. The safety timer feature can be disabled through I<sup>2</sup>C by setting EN\_TIMER bit

During input voltage, current, JEITA cool or thermal regulation, the safety timer counts at half clock rate as the actual charge current is likely to be below the register setting. For example, if the charger is in input current regulation (IDPM\_STAT = 1) throughout the whole charging cycle, and the safety time is set to 5 hours, the safety timer will expire in 10 hours. This half clock rate feature can be disabled by writing 0 to TMR2X\_EN bit.

During the fault, timer is suspended. Once the fault goes away, fault resumes. If user stops the current charging cycle, and start again, timer gets reset (toggle CE pin or CHRG\_CONFIG bit).



### 9.4 Device Functional Modes

#### 9.4.1 Narrow VDC Architecture

The device deploys Narrow VDC architecture (NVDC) with BATFET separating system from battery. The minimum system voltage is set by SYS\_Min bits. Even with a fully depleted battery, the system is regulated above the minimum system voltage.

When the battery is below minimum system voltage setting, the BATFET operates in linear mode (LDO mode), and the system is typically 180 mV above the minimum system voltage setting. As the battery voltage rises above the minimum system voltage, BATFET is fully on and the voltage difference between the system and battery is the VDS of BATFET.

When the battery charging is disabled and above minimum system voltage setting or charging is terminated, the system is always regulated at typically 50mV above battery voltage. The status register VSYS\_STAT bit goes high when the system is in minimum system voltage regulation.

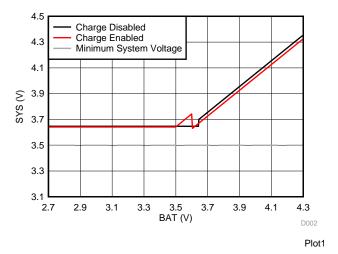


图 15. System Voltage vs Battery Voltage

#### 9.4.2 Dynamic Power Management

To meet maximum current limit in USB spec and avoid over loading the adapter, the device features Dynamic Power management (DPM), which continuously monitors the input current and input voltage. When input source is over-loaded, either the current exceeds the input current limit (IIDPM) or the voltage falls below the input voltage limit (VINDPM). The device then reduces the charge current until the input current falls below the input current limit and the input voltage rises above the input voltage limit.

When the charge current is reduced to zero, but the input source is still overloaded, the system voltage starts to drop. Once the system voltage falls below the battery voltage, the device automatically enters the supplement mode where the BATFET turns on and battery starts discharging so that the system is supported from both the input source and battery.

During DPM mode, the status register bits VDPM\_STAT (VINDPM) or IDPM\_STAT (IINDPM) goes high. 

16 shows the DPM response with 9-V/1.2-A adapter, 3.2-V battery, 2.8-A charge current and 3.5-V minimum system voltage setting.

## TEXAS INSTRUMENTS

## Device Functional Modes (接下页)

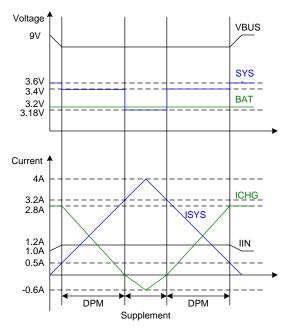


图 16. DPM Response

## 9.4.3 Supplement Mode

When the system voltage falls 180 mV (VBAT > VSYSMin) or 45 mV (VBAT < VSYSMin) below the battery voltage, the BATFET turns on and the BATFET gate is regulated the gate drive of BATFET so that the minimum BATFET VDS stays at 30 mV when the current is low. This prevents oscillation from entering and exiting the supplement mode.

As the discharge current increases, the BATFET gate is regulated with a higher voltage to reduce RDSON until the BATFET is in full conduction. At this point onwards, the BATFET VDS linearly increases with discharge current. 

17 shows the V-I curve of the BATFET gate regulation operation. BATFET turns off to exit supplement mode when the battery is below battery depletion threshold.

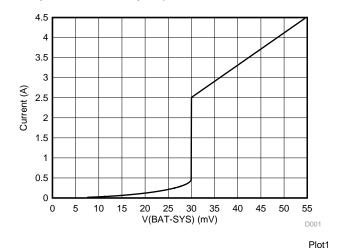


图 17. BAFET V-I Curve



## Device Functional Modes (接下页)

## 9.4.4 Shipping Mode and QON Pin

## 9.4.4.1 BATFET Disable Mode (Shipping Mode)

To extend battery life and minimize power when system is powered off during system idle, shipping, or storage, the device can turn off BATFET so that the system voltage is zero to minimize the battery leakage current. When the host set BATFET\_DIS bit, the charger can turn off BATFET immediately or delay by t<sub>SM\_DLY</sub> as configured by BATFET\_DLY bit.

### 9.4.4.2 BATFET Enable (Exit Shipping Mode)

When the BATFET is disabled (in shipping mode) and indicated by setting BATFET\_DIS, one of the following events can enable BATFET to restore system power:

- 1. Plug in adapter
- 2. Clear BATFET DIS bit
- 3. Set REG\_RST bit to reset all registers including BATFET\_DIS bit to default (0)
- 4. A logic high to low transition on  $\overline{\text{QON}}$  pin with  $t_{\text{SHIPMODE}}$  deglitch time to enable BATFET to exit shipping mode

## 9.4.4.3 BATFET Full System Reset

The BATFET functions as a load switch between battery and system when input source is not pluggeD–in. By changing the state of BATFET from on to off, systems connected to SYS can be effectively forced to have a power-on-reset. The QON pin supports push-button interface to reset system power without host by changing the state of BATFET.

When the  $\overline{\text{QON}}$  pin is driven to logic low for  $t_{\text{QON\_RST}}$  while input source is not plugged in and BATFET is enabled (BATFET\_DIS = 0), the BATFET is turned off for  $t_{\text{BATFET\_RST}}$  and then it is re-enabled to reset system power. This function can be disabled by setting BATFET\_RST\_EN bit to 0.

## 9.4.4.4 QON Pin Operations

The QON pin incorporates two functions to control BATFET.

- 1. BATFET Enable: A  $\overline{\text{QON}}$  logic transition from high to low with longer than  $t_{\text{SHIPMODE}}$  deglitch turns on BATFET and exit shipping mode. When exiting shipping mode, HIZ is enabled (EN\_HIZ = 1) as well. HIZ can be disabled (EN\_HIZ = 0) by the host after exiting shipping mode. OTG cannot be enabled (OTG\_CONFIG = 1) until HIZ is disabled.
- 2. BATFET Reset: When  $\overline{\text{QON}}$  is driven to logic low by at least  $t_{\text{QON\_RST}}$  while adapter is not plugged in (and BATFET\_DIS = 0), the BATFET is turned off for  $t_{\text{BATFET\_RST}}$ . The BATFET is re-enabled after  $t_{\text{BATFET\_RST}}$  duration. This function allows systems connected to SYS to have power-on-reset. This function can be disabled by setting BATFET\_RST\_EN bit to 0.
- 18 shows the sample external configurations for each.

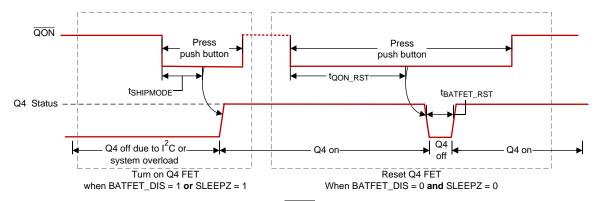


图 18. QON Timing

## TEXAS INSTRUMENTS

## Device Functional Modes (接下页)

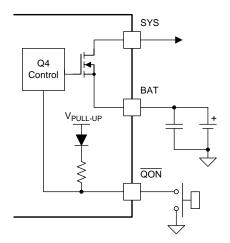


图 19. QON Circuit

## 9.4.5 Status Outputs (PG, STAT, INT)

## 9.4.5.1 Power Good indicator ( PGPin PG STAT Bit)

The PG\_STAT bit goes HIGH to indicate a good input source when:

- VBUS above V<sub>VBUS UVLO</sub>
- · VBUS above battery (not in sleep)
- VBUS below V<sub>VAC OV</sub> threshold
- VBUS above V<sub>VBUSMin</sub> (typical 3.8 V) when I<sub>BADSRC</sub> (typical 30 mA) current is applied (not a poor source)
- Completed input Source Type Detection

## 9.4.5.2 Charging Status indicator (STAT)

The device indicates charging state on the open drain STAT pin. The STAT pin can drive LED. The STAT pin function can be disabled by setting the EN\_ICHG\_MON bits = 11.

表 5. STAT Pin State

CHARGING STATE	STAT INDICATOR
Charging in progress (including recharge)	LOW
Charging complete	HIGH
Sleep mode, charge disable	HIGH
Charge suspend (input overvoltage, TS fault, timer fault or system overvoltage) Boost Mode suspend (due to TS fault)	Blinking at 1 Hz

## 9.4.5.3 Interrupt to Host (INT)

In some applications, the host does not always monitor the charger operation. The INT pulse notifies the system on the device operation. The following events will generate  $256-\mu s$  INT pulse.

- USB/adapter source identified (through DPDM detection)
- Good input source detected
  - VBUS above battery (not in sleep)
  - VBUS below V<sub>VAC OV</sub> threshold
  - VBUS above V<sub>VBUSMin</sub> (typical 3.8 V) when I<sub>BADSRC</sub> (typical 30 mA) current is applied (not a poor source)
- · input removed
- Charge Complete
- Any FAULT event in REG09



VINDPM / IINDPM event detected (maskable)

When a fault occurs, the charger device sends out INT and keeps the fault state in REG09 until the host reads the fault register. Before the host reads REG09 and all the faults are cleared, the charger device would not send any INT upon new faults. To read the current fault status, the host has to read REG09 two times consecutively. The first read reports the pre-existing fault register status and the second read reports the current fault register status.

#### 9.5 Protections

## 9.5.1 Voltage and Current Monitoring in Converter Operation

The device closely monitors the input and system voltage, as well as internal FET currents for safe buck and boost mode operation.

### 9.5.1.1 Voltage and Current Monitoring in Buck Mode

#### 9.5.1.1.1 Input Overvoltage (ACOV)

If VBUS voltage exceeds V<sub>VAC OV</sub> (programmable via OVP[2:0] bits), the device stops switching immediately.

During input overvoltage event (ACOV), the fault register CHRG\_FAULT bits are set to 01. An INT pulse is asserted to the host. The device will automatically resume normal operation once the input voltage drops back below the OVP threshold.

#### 9.5.1.1.2 System Overvoltage Protection (SYSOVP)

The charger device clamps the system voltage during load transient so that the components connect to system would not be damaged due to high voltage. SYSOVP threshold is 350 mV above minimum system regulation voltage when the system is regulate at V<sub>SYSMIN</sub>. Upon SYSOVP, converter stops switching immediately to clamp the overshoot. The charger provides 30 mA discharge current to bring down the system voltage.

## 9.5.2 Voltage and Current Monitoring in Boost Mode

The device closely monitors the VBUS voltage, as well as RBFET and LSFET current to ensure safe boost mode operation.

#### 9.5.2.1 VBUS Soft Start

When the boost function is enabled, the device soft-starts boost mode to avoid inrush current.

#### 9.5.2.2 VBUS Output Protection

The device monitors boost output voltage and other conditions to provide output short circuit and overvoltage protection. The Boost build in accurate constant current regulation to allow OTG to adaptive to various types of load. If short circuit is detected on VBUS, the Boost turns off and retry 7 times. If retries are not successful, OTG is disabled with OTG\_CONFIG bit cleared. In addition, the BOOST\_FAULT bit is set and INT pulse is generated. The BOOST\_FAULT bit can be cleared by host by re-enabling boost mode.

#### 9.5.2.3 Boost Mode Overvoltage Protection

When the VBUS voltage rises above regulation target and exceeds VOTG\_OVP, the device enters overvoltage protection which stops switching, clears OTG\_CONFIG bit and exits boost mode. At Boost overvoltage duration, the fault register bit (BOOST\_FAULT) is set high to indicate fault in boost operation. An INT is also asserted to the host.

## TEXAS INSTRUMENTS

## Protections (接下页)

### 9.5.3 Thermal Regulation and Thermal Shutdown

#### 9.5.3.1 Thermal Protection in Buck Mode

The BQ25601D monitors the internal junction temperature  $T_J$  to avoid overheat the chip and limits the IC surface temperature in buck mode. When the internal junction temperature exceeds thermal regulation limit (110°C), the device lowers down the charge current. During thermal regulation, the actual charging current is usually below the programmed battery charging current. Therefore, termination is disabled, the safety timer runs at half the clock rate, and the status register THERM\_STAT bit goes high.

Additionally, the device has thermal shutdown to turn off the converter and BATFET when IC surface temperature exceeds  $T_{SHUT}(160^{\circ}C)$ . The fault register CHRG\_FAULT is set to 1 and an  $\overline{INT}$  is asserted to the host. The BATFET and converter is enabled to recover when IC temperature is  $T_{SHUT\_HYS}$  (30°C) below  $T_{SHUT}(160^{\circ}C)$ .

## 9.5.3.2 Thermal Protection in Boost Mode

The device monitors the internal junction temperature to provide thermal shutdown during boost mode. When IC junction temperature exceeds  $T_{SHUT}$  (160°C), the boost mode is disabled by setting OTG\_CONFIG bit low and BATFET is turned off. When IC junction temperature is below  $T_{SHUT}$  (160°C) -  $T_{SHUT\_HYS}$  (30°C), the BATFET is enabled automatically to allow system to restore and the host can re-enable OTG\_CONFIG bit to recover.

## 9.5.4 Battery Protection

### 9.5.4.1 Battery overvoltage Protection (BATOVP)

The battery overvoltage limit is clamped at 4% above the battery regulation voltage. When battery over voltage occurs, the charger device immediately disables charging. The fault register BAT\_FAULT bit goes high and an INT is asserted to the host.

## 9.5.4.2 Battery Over-Discharge Protection

When battery is discharged below  $V_{BAT\_DPL\_FALL}$ , the BATFET is turned off to protect battery from over discharge. To recover from over-discharge latch-off, an input source plug-in is required at VBUS. The battery is charged with  $I_{SHORT}$  (typically 100 mA) current when the VBAT < VSHORT, or precharge current as set in IPRECHG register when the battery voltage is between  $V_{SHORTZ}$  and  $V_{BAT\_LOWV}$ .

## 9.5.4.3 System Over-Current Protection

When the system is shorted or significantly overloaded (IBAT > IBATOP) and the current exceeds BATFET overcurrent limit, the BATFET latches off. Section BATFET Enable (Exit Shipping Mode) can reset the latch-off condition and turn on BATFET.

## 9.6 Programming

## 9.6.1 Serial Interface

The device uses I<sup>2</sup>C compatible interface for flexible charging parameter programming and instantaneous device status reporting. I<sup>2</sup>CTM is a bi-directional 2-wire serial interface developed by Philips Semiconductor (now NXP Semiconductors). Only two bus lines are required: a serial data line (SDA) and a serial clock line (SCL). Devices can be considered as masters or slaves when performing data transfers. A master is the device which initiates a data transfer on the bus and generates the clock signals to permit that transfer. At that time, any device addressed is considered a slave.

The device operates as a slave device with address 6BH, receiving control inputs from the master device like micro controller or a digital signal processor through REG00-REG0B. Register read beyond REG0B (0x0B) returns 0xFF. The I<sup>2</sup>C interface supports both standard mode (up to 100 kbits), and fast mode (up to 400 kbits). connecting to the positive supply voltage via a current source or pull-up resistor. When the bus is free, both lines are HIGH. The SDA and SCL pins are open drain.



## Programming (接下页)

### 9.6.1.1 Data Validity

The data on the SDA line must be stable during the HIGH period of the clock. The HIGH or LOW state of the data line can only change when the clock signal on the SCL line is LOW. One clock pulse is generated for each data bit transferred.

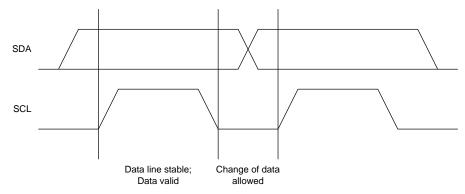


图 20. Bit Transfer on the I2C Bus

#### 9.6.1.2 START and STOP Conditions

All transactions begin with a START (S) and can be terminated by a STOP (P). A HIGH to LOW transition on the SDA line while SCI is HIGH defines a START condition. A LOW to HIGH transition on the SDA line when the SCL is HIGH defines a STOP condition. START and STOP conditions are always generated by the master. The bus is considered busy after the START condition, and free after the STOP condition.

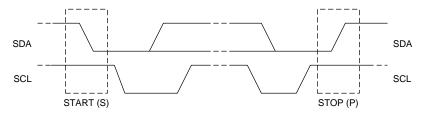


图 21. TS START and STOP Conditions

## 9.6.1.3 Byte Format

Every byte on the SDA line must be 8 bits long. The number of bytes to be transmitted per transfer is unrestricted. Each byte has to be followed by an Acknowledge bit. Data is transferred with the Most Significant Bit (MSB) first. If a slave cannot receive or transmit another complete byte of data until it has performed some other function, it can hold the clock line SCL low to force the mAster into a wait state (clock stretching). Data transfer then continues when the slave is ready for another byte of data and release the clock line SCL.

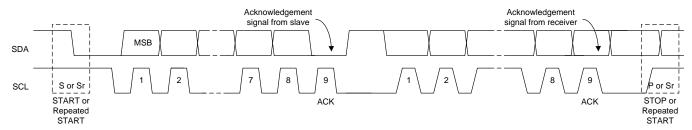


图 22. Data Transfer on the I<sup>2</sup>C Bus

## TEXAS INSTRUMENTS

## Programming (接下页)

### 9.6.1.4 Acknowledge (ACK) and Not Acknowledge (NACK)

The acknowledge takes place after every byte. The acknowledge bit allows the receiver to signal the transmitter that the byte was successfully received and another byte may be sent. All clock pulses, including the acknowledge ninth clock pulse, are generated by the master. The transmitter releases the SDA line during the acknowledge clock pulse so the receiver can pull the SDA line LOW and it remains stable LOW during the HIGH period of this clock pulse.

When SDA remains HIGH during the ninth clock pulse, this is the Not Acknowledge signal. The master can then generate either a STOP to abort the transfer or a repeated START to start a new transfer.

## 9.6.1.5 Slave Address and Data Direction Bit

After the START, a slave address is sent. This address is 7 bits long followed by the eighth bit as a data direction bit (bit R/W). A zero indicates a transmission (WRITE) and a one indicates a request for data (READ).

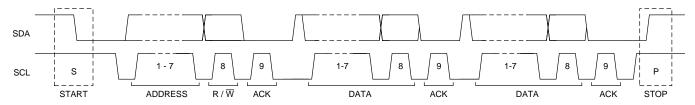


图 23. Complete Data Transfer

## 9.6.1.6 Single Read and Write

If the register address is not defined, the charger IC send back NACK and go back to the idle state.

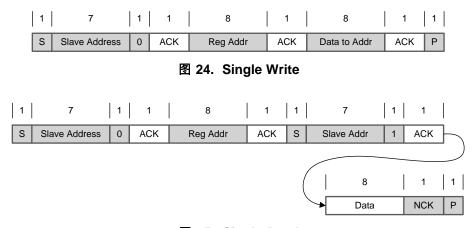


图 25. Single Read

#### 9.6.1.7 Multi-Read and Multi-Write

The charger device supports multi-read and multi-write on REG00 through REG0B.

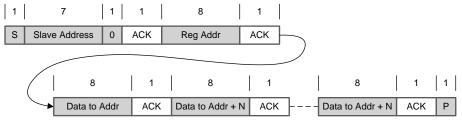


图 26. Multi-Write



## Programming (接下页)

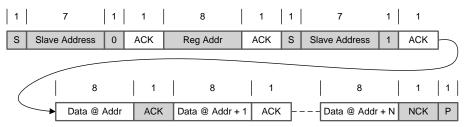


图 27. Multi-Read

REG09 is a fault register. It keeps all the fault information from last read until the host issues a new read. For example, if Charge Safety Timer Expiration fault occurs but recovers later, the fault register REG09 reports the fault when it is read the first time, but returns to normal when it is read the second time. in order to get the fault information at present, the host has to read REG09 for the second time. The only exception is NTC\_FAULT which always reports the actual condition on the TS pin. in addition, REG09 does not support multi-read and multi-write.

## TEXAS INSTRUMENTS

## 9.7 Register Maps

I<sup>2</sup>C Slave Address: 6BH

## 9.7.1 REG00 (address = 00) [reset = 00010111]

## 图 28. REG00 Register

7	6	5	4	3	2	1	0
EN_HIZ	EN_ICHG_MO	EN_ICHG_MO	IINDPM[4]	IINDPM[3]	IINDPM[2]	IINDPM[1]	IINDPM[0]
	N[1]	N[0]					
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

## 表 6. REG00 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment
7	EN_HIZ	0	R/W	by REG_RST by Watchdog	0 – Disable, 1 – Enable	Enable HIZ Mode 0 – Disable (default) 1 – Enable
6	EN_ICHG_MON[1]	0	R/W	by REG_RST	00 - Enable STAT pin function	
5	EN_ICHG_MON[0]	0	R/W	by REG_RST	(default) 01 - Reserved 10 - Reserved 11 - Disable STAT pin function (float pin)	
4	IINDPM[4]	1	R/W	by REG_RST	1600 mA	Input Current Limit
3	IINDPM[3]	0	R/W	by REG_RST	800 mA	Offset: 100 mA
2	IINDPM[2]	1	R/W	by REG_RST	400 mA	Range: 100 mA (000000) – 3.2 A (11111)
1	IINDPM[1]	1	R/W	by REG_RST	200 mA	Default:2400 mA (10111),
0	IINDPM[0]	1	R/W	by REG_RST	100 mA	maximum input current limit, not typical.  IINDPM bits are changed automatically after input source detection is completed Host can over-write IINDPM register bits after input source detection is completed.

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



## 9.7.2 REG01 (address = 01) [reset = 00011010]

## 图 29. REG01 Register

7	6	5	4	3	2	1	0
PFM _DIS	WD_RST	OTG_CONFIG	CHG_CONFIG	SYS_Min[2]	SYS_Min[1]	SYS_Min[0]	Min_V <sub>BAT</sub> _SEL
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

## 表 7. REG01 Field Descriptions

~ · · · · · · · · · · · · · · · · · · ·								
Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment		
7	PFM _DIS	0	R/W	by REG_RST	0 – Enable PFM 1 – Disable PFM	Default: 0 - Enable		
6	WD_RST	0	R/W	by REG_RST by Watchdog	I <sup>2</sup> C Watchdog Timer Reset 0 – Normal ; 1 – Reset	Default: Normal (0) Back to 0 after watchdog timer reset		
5	OTG_CONFIG	0	R/W	by REG_RST by Watchdog	0 – OTG Disable 1 – OTG Enable	Default: OTG disable (0) Note: 1. OTG_CONFIG would over-ride Charge Enable Function in CHG_CONFIG		
4	CHG_CONFIG	1	R/W	by REG_RST by Watchdog	0 - Charge Disable 1- Charge Enable	Default: Charge Battery (1) Note: 1. Charge is enabled when both CE pin is pulled low AND CHG_CONFIG bit is 1.		
3	SYS_Min[2]	1	R/W	by REG_RST		000: 2.6 V		
2	SYS_Min[1]	0	R/W	by REG_RST		001: 2.8 V 010: 3 V		
1	SYS_Min[0]	1	R/W	by REG_RST	System Minimum Voltage	011: 3.2 V 100: 3.4 V 101: 3.5 V 110: 3.6 V 111: 3.7 V Default: 3.5 V (101)		
0	Min_V <sub>BAT</sub> _SEL	0	R/W	by REG_RST	0 – 2.8 V BAT falling, 1 – 2.5 V BAT falling	Minimum battery voltage for OTG mode. Default falling 2.8 V (0); Rising threshold 3.0 V (0)		

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



## 9.7.3 REG02 (address = 02) [reset = 10100010]

## 图 30. REG02 Register

7	6	5	4	3	2	1	0
BOOST_LIM	Q1_FULLON	ICHG[5]	ICHG[4]	ICHG[3]	ICHG[2]	ICHG[1]	ICHG[0]
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

## 表 8. REG02 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment	
7	BOOST_LIM	1	R/W	by REG_RST by Watchdog	0 = 0.5 A 1 = 1.2 A	Default: 1.2 A (1) Note: The current limit options listed are minimum current limit specs.	
6	Q1_FULLON	0	R/W	by REG_RST	0 – Use higher Q1 RDSON when programmed IINDPM < 700mA (better accuracy) 1 – Use lower Q1 RDSON always (better efficiency)	In boost mode, full FET is always used and this bit has no effect	
5	ICHG[5]	1	R/W	by REG_RST by Watchdog	1920 mA		
4	ICHG[4]	0	R/W	by REG_RST by Watchdog	960 mA	Fast Charge Current Default: 2040mA (100010)	
3	ICHG[3]	0	R/W	by REG_RST by Watchdog	480 mA	Range: 0 mA (0000000) – 3000 mA (110010)  Note:  I <sub>CHG</sub> = 0 mA disables charge.  I <sub>CHG</sub> > 3000 mA (110010 clamped to register value 3000 mA (110010))	
2	ICHG[2]	0	R/W	by REG_RST by Watchdog	240 mA		
1	ICHG[1]	1	R/W	by REG_RST by Watchdog	120 mA		
0	ICHG[0]	0	R/W	by REG_RST by Watchdog	60 mA		

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



## 9.7.4 REG03 (address = 03) [reset = 00100010]

## 图 31. Register REG03

7	6	5	4	3	2	1	0
IPRECHG[3]	IPRECHG[2]	IPRECHG[1]	IPRECHG[0]	ITERM[3]	ITERM[2]	ITERM[1]	ITERM[0]
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

### 表 9. REG03 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment
7	IPRECHG[3]	0	R/W	by REG_RST by Watchdog	480 mA	
6	IPRECHG[2]	0	R/W	by REG_RST by Watchdog	240 mA	Precharge Current Default: 180 mA (0010)
5	IPRECHG[1]	1	R/W	by REG_RST by Watchdog	120 mA	Offset: 60 mA Note: IPRECHG > 780 mA clamped to 780 mA (1100)
4	IPRECHG[0]	0	R/W	by REG_RST by Watchdog	60 mA	
3	ITERM[3]	0	R/W	by REG_RST by Watchdog	480 mA	
2	ITERM[2]	0	R/W	by REG_RST by Watchdog	240 mA	Termination Current
1	ITERM[1]	1	R/W	by REG_RST by Watchdog	120 mA	Default: 180 mA (0010) Offset: 60 mA
0	ITERM[0]	0	R/W	by REG_RST by Watchdog	60 mA	

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



# 9.7.5 REG04 (address = 04) [reset = 01011000]

## 图 32. Register REG04

7	6	5	4	3	2	1	0
VREG[4]	VREG[3]	VREG[2]	VREG[1]	VREG[0]	TOPOFF_TIME R[1]	TOPOFF_TIME R[0]	VRECHG
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

## 表 10. REG04 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment	
7	VREG[4]	0	R/W	by REG_RST by Watchdog	512 mV	Charge Voltage	
6	VREG[3]	1	R/W	by REG_RST by Watchdog	256 mV	Offset: 3.847 V Range: 3.847 V to 4.615 V (11000)	
5	VREG[2]	0	R/W	by REG_RST by Watchdog	128 mV	Default: 4.199 V (01011) Special Value:	
4	VREG[1]	1	R/W	by REG_RST by Watchdog	64 mV	(01111): 4.343 V Note: Value above 11000 (4.615	
3	VREG[0]	1	R/W	by REG_RST by Watchdog	32 mV	V) is clamped to register value 11000 (4.615 V)	
2	TOPOFF_TIMER[1]	0	R/W	by REG_RST by Watchdog	00 – Disabled (Default) 01 – 15 minutes	The extended time following the termination condition is met. When	
1	TOPOFF_TIMER[0]	0	R/W	by REG_RST by Watchdog	10 – 30 minutes 11 – 45 minutes	disabled, charge terminated when termination conditions are met	
0	VRECHG	0	R/W	by REG_RST by Watchdog	0 – 100 mV 1 – 200 mV	Recharge threshold Default: 100mV (0)	

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



# 9.7.6 REG05 (address = 05) [reset = 10011111]

## 图 33. Register REG05

7	6	5	4	3	2	1	0
EN_TERM	Reserved	WATCHDOG[1]	WATCHDOG[0]	EN_TIMER	CHG_TIMER	TREG	JEITA_ISET
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

### 表 11. REG05 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment
7	EN_TERM	1	R/W	by REG_RST by Watchdog	0 – Disable 1 – Enable	Default: Enable termination (1)
6	Reserved	0	R/W	by REG_RST by Watchdog	Reserved	Reserved
5	WATCHDOG[1]	0	R/W	by REG_RST by Watchdog	00 – Disable timer, 01 – 40 s, 10 –	Default: 40 s (01)
4	WATCHDOG[0]	1	R/W	by REG_RST by Watchdog	80 s,11 – 160 s	Delault. 40 5 (01)
3	EN_TIMER	1	R/W	by REG_RST by Watchdog	0 – Disable 1 – Enable both fast charge and precharge timer	Default: Enable (1)
2	CHG_TIMER	1	R/W	by REG_RST by Watchdog	0 – 5 hrs 1 – 10 hrs	Default: 10 hours (1)
1	TREG	1	R/W	by REG_RST by Watchdog	Thermal Regulation Threshold: 0 - 90°C 1 - 110°C	Default: 110°C (1)
0	JEITA_ISET (0C-10C)	1	R/W	by REG_RST by Watchdog	0 – 50% of ICHG 1 – 20% of ICHG	Default: 20% (1)

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



## 9.7.7 REG06 (address = 06) [reset = 01100110]

## 图 34. Register REG06

7	6	5	4	3	2	1	0
OVP[1]	OVP[0]	BOOSTV[1]	BOOSTV[0]	VINDPM[3]	VINDPM[2]	VINDPM[1]	VINDPM[0]
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

### 表 12. REG06 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment
7	OVP[1]	0	R/W	by REG_RST		VAC OVP threshold:
6	OVP[0]	1	R/W	by REG_RST	Default: 6.5V (01)	00 - 5.5 V 01 - 6.5 V (5-V input) 10 - 10.5 V (9-V input) 11 - 14 V (12-V input)
5	BOOSTV[1]	1	R/W	by REG_RST		Boost Regulation Voltage:
4	BOOSTV[0]	0	R/W	by REG_RST		00 - 4.85V 01 - 5.00V 10 - 5.15V 11 - 5.30V
3	VINDPM[3]	0	R/W	by REG_RST	800 mV	Absolute VINDPM Threshold
2	VINDPM[2]	1	R/W	by REG_RST	400 mV	Offset: 3.9 V
1	VINDPM[1]	1	R/W	by REG_RST	200 mV	Range: 3.9 V (0000) – 5.4 V (1111)
0	VINDPM[0]	0	R/W	by REG_RST	100 mV	Default: 4.5V (0110)

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



# 9.7.8 REG07 (address = 07) [reset = 01001100]

## 图 35. Register REG07

7	6	5	4	3	2	1	0
IINDET_EN	TMR2X_EN	BATFET_DIS	JEITA_VSET	BATFET_DLY	BATFET_RST_ EN	VDPM_BAT_T RACK[1]	VDPM_BAT_T RACK[0]
R/W	R/W	R/W	R/W	R/W	R/W	R/W	R/W

### 表 13. REG07 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description	Comment
7	IINDET_EN	0	R/W	by REG_RST by Watchdog	0 - Not in input current limit detection 1 - Force input current limit detection when VBUS is present	Returns to 0 after input detection is complete
6	TMR2X_EN	1	R/W	by REG_RST by Watchdog 0 – Disable 1 – Safety timer slowed by 2X during input DPM (both V and I) or JEITA cool, or thermal regulation		
5	BATFET_DIS	0	R/W	by REG_RST	0 – Allow Q4 turn on, 1 – Turn off Q4 with t <sub>BATFET_DLY</sub> delay time (REG07[3])	Default: Allow Q4 turn on(0)
4	JEITA_VSET (45C-60C)	0	R/W	by REG_RST by Watchdog	0 – Set Charge Voltage to 4.1V (max), 1 – Set Charge Voltage to VREG	
3	BATFET_DLY	1	R/W	by REG_RST	0 – Turn off BATFET immediately when BATFET_DIS bit is set 1 –Turn off BATFET after t <sub>BATFET_DLY</sub> (typ. 10 s) when BATFET_DIS bit is set	Default: 1 Turn off BATFET after t <sub>BATFET_DLY</sub> (typ. 10 s) when BATFET_DIS bit is set
2	BATFET_RST_EN	1	R/W	by REG_RST by Watchdog	0 – Disable BATFET reset function 1 – Enable BATFET reset function	Default: 1 Enable BATFET reset function
1	VDPM_BAT_TRACK[1]	0	R/W	by REG_RST	00 - Disable function (VINDPM set	Sets VINDPM to track BAT
0	VDPM_BAT_TRACK[0]	0	R/W	by register) vo (01 - VBAT + 200mV of (05 of		voltage. Actual VINDPM is higher of register value and VBAT + VDPM_BAT_TRACK

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



# 9.7.9 REG08 (address = 08) [reset = xxxxxxxx]

## 图 36. Register REG08

7	6	5	4	3	2	1	0
VBUS_STAT[2]	VBUS_STAT[1]	VBUS_STAT[0]	CHRG_STAT[1	CHRG_STAT[0	PG_STAT	THERM_STAT	VSYS_STAT
			]	]			
R	R	R	R	R	R	R	R

### 表 14. REG08 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description
7	VBUS_STAT[2]	Х	R	NA	VBUS Status register
6	VBUS_STAT[1]	Х	R	NA	BQ25601D 000: No input
5	VBUS_STAT[0]	x	R	NA	001: USB Host SDP 010: USB CDP: (1.5A) 011: USB DCP (2.4 A) 101: Unknown Adapter (500 mA) 110: Non-Standard Adapter (1A/2A/2.1A/2.4A) 111: OTG Software current limit is reported in IINDPM register
4	CHRG_STAT[1]	x	R	NA	Charging status:
3	CHRG_STAT[0]	x	R	NA	00 – Not Charging 01 – Pre-charge (< V <sub>BATLOWV</sub> ) 10 – Fast Charging 11 – Charge Termination
2	PG_STAT	х	R	NA	Power Good status: 0 – Power Not Good 1 – Power Good
1	THERM_STAT	х	R	NA	0 – Not in ther mAl regulation 1 – in ther mAl regulation
0	VSYS_STAT	х	R	NA	0 - Not in VSYSMin regulation (BAT > VSYSMin) 1 - in VSYSMin regulation (BAT < VSYSMin)

<sup>(1)</sup> LEGEND: R/W = Read/Write



# 9.7.10 REG09 (address = 09) [reset = xxxxxxxx]

## 图 37. Register REG09

7	6	5	4	3	2	1	0
WATCHDOG_F	BOOST_FAUL	CHRG_FAULT[	CHRG_FAULT[	BAT_FAULT	NTC_FAULT[2]	NTC_FAULT[1]	NTC_FAULT[0]
AULT	T	1]	0]				
R	R	R	R	R	R	R	R

### 表 15. REG09 Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description
7	WATCHDOG_FAULT	Х	R	NA	0 – Normal, 1- Watchdog timer expiration
6	BOOST_FAULT	х	R	NA	0 – Normal, 1 – VBUS overloaded in OTG, or VBUS OVP, or battery is too low (any conditions that we cannot start boost function)
5	CHRG_FAULT[1]	Х	R	NA	00 - Normal, 01 - input fault (VAC OVP or VBAT < VBUS < 3.8 V), 10
4	CHRG_FAULT[0]	Х	R	NA	- Thermal shutdown, 11 – Charge Safety Timer Expiration
3	BAT_FAULT	Х	R	NA	0 – Normal, 1 – BATOVP
2	NTC_FAULT[2]	Х	R	NA	JEITA
1	NTC_FAULT[1]	Х	R	NA	000 – Normal, 010 – Warm, 011 – Cool, 101 – Cold, 110 – Hot (Buck mode)
0	NTC_FAULT[0]	Х	R	NA	000 – Normal, 101 – Cold, 110 – Hot (Boost mode)

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



## 9.7.11 REG0A (address = 0A) [reset = xxxxxx00]

## 图 38. Register REG0A

7	6	5	4	3	2	1	0
VBUS_GD	VINDPM_STAT	IINDPM_STAT	Reserved	TOPOFF_ACTI VE	ACOV_STAT	VINDPM_INT_ MASK	IINDPM_INT_ MASK
R	R	R	R	R	R	R/W	R/W

### 表 16. REG0A Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description
7	VBUS_GD	х	R	NA	0 – Not VBUS attached, 1 – VBUS Attached
6	VINDPM_STAT	Х	R	NA	0 – Not in VINDPM, 1 – in VINDPM
5	IINDPM_STAT	Х	R	NA	0 – Not in IINDPM, 1 – in IINDPM
4	Reserved	Х	R	NA	
3	TOPOFF_ACTIVE	х	R	NA	0 – Top off timer not counting. 1 – Top off timer counting
2	ACOV_STAT	х	R	NA	0 – Device is NOT in ACOV 1 – Device is in ACOV
1	VINDPM_INT_ MASK	0	R/W	by REG_RST	0 - Allow VINDPM INT pulse 1 - Mask VINDPM INT pulse
0	IINDPM_INT_ MASK	0	R/W	by REG_RST	0 - Allow IINDPM INT pulse 1 - Mask IINDPM INT pulse

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only



# 9.7.12 REG0B (address = 0B) [reset = 00111xxx]

## 图 39. Register REG0B

7	6	5	4	3	2	1	0
REG_RST	PN[3]	PN[2]	PN[1]	PN[0]	Reserved	DEV_REV[1]	DEV_REV[0]
R/W	R	R	R	R	R	R	R

## 表 17. REG0B Field Descriptions

Bit	Field	POR	Type <sup>(1)</sup>	Reset	Description
7	REG_RST	0	R/W	NA	Register reset 0 – Keep current register setting 1 – Reset to default register value and reset safety timer Note: Bit resets to 0 after register reset is completed
6	PN[3]	0	R	NA	
5	PN[2]	1	R	NA	PO05004D - 0444
4	PN[1]	1	R	NA	BQ25601D: 0111
3	PN[0]	1	R	NA	
2	Reserved	Х	R	NA	
1	DEV_REV[1]	Х	R	NA	
0	DEV_REV[0]	Х	R	NA	

<sup>(1)</sup> LEGEND: R/W = Read/Write; R = Read only

ZHCSIJ0 – JULY 2018 www.ti.com.cn



#### 10 Application and Implementation

注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

#### 10.1 Application information

A typical application consists of the device configured as an I<sup>2</sup>C controlled power path management device and a single cell battery charger for Li-lon and Li-polymer batteries used in a wide range of smart phones and other portable devices. It integrates an input reverse-block FET (RBFET, Q1), high-side switching FET (HSFET, Q2), low-side switching FET (LSFET, Q3), and battery FET (BATFET Q4) between the system and battery. The device also integrates a bootstrap diode for the high-side gate drive.

#### 10.2 Typical Application

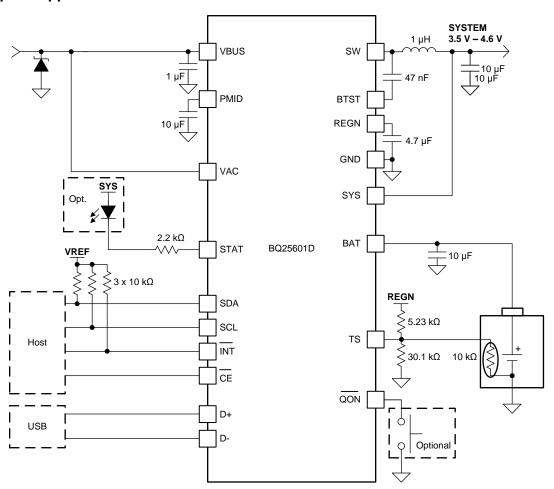


图 40. Power Path Management Application

#### 10.2.1 Design Requirements

表 18. Design Requirements

PARAMETER	VALUE
Input Voltage	3.9V to 13.5V
Input Current	3.0A
Fast Charge Current	3.0A
Battery Regulation Voltage	4.2V

#### 10.2.2 Detailed Design Procedure

#### 10.2.2.1 Custom Design With WEBENCH® Tools

Click here to create a custom design using the BQ25601D device with the WEBENCH® Power Designer.

- 1. Start by entering the input voltage (V<sub>IN</sub>), output voltage (V<sub>OUT</sub>), and output current (I<sub>OUT</sub>) requirements.
- 2. Optimize the design for key parameters such as efficiency, footprint, and cost using the optimizer dial.
- 3. Compare the generated design with other possible solutions from Texas Instruments.

The WEBENCH Power Designer provides a customized schematic along with a list of materials with real-time pricing and component availability.

In most cases, these actions are available:

ZHCSIJ0 – JULY 2018 www.ti.com.cn



- Run electrical simulations to see important waveforms and circuit performance
- Run thermal simulations to understand board thermal performance
- · Export customized schematic and layout into popular CAD formats
- Print PDF reports for the design, and share the design with colleagues

Get more information about WEBENCH tools at www.ti.com/WEBENCH.

#### 10.2.2.2 Inductor Selection

The 1.5-MHz switching frequency allows the use of small inductor and capacitor values to maintain an inductor saturation current higher than the charging current ( $I_{CHG}$ ) plus half the ripple current ( $I_{RIPPLE}$ ):

$$I_{SAT} \ge I_{CHG} + (1/2) I_{RIPPIF}$$
(3)

The inductor ripple current depends on the input voltage ( $V_{VBUS}$ ), the duty cycle ( $D = V_{BAT}/V_{VBUS}$ ), the switching frequency ( $f_S$ ) and the inductance (L).

$$I_{RIPPLE} = \frac{V_{IN} \times D \times (1 - D)}{fs \times L}$$
(4)

The maximum inductor ripple current occurs when the duty cycle (D) is 0.5 or approximately 0.5. Usually inductor ripple is designed in the range between 20% and 40% maximum charging current as a trade-off between inductor size and efficiency for a practical design.

#### 10.2.2.3 Input Capacitor

Design input capacitance to provide enough ripple current rating to absorb input switching ripple current. The worst case RMS ripple current is half of the charging current when duty cycle is 0.5. If the converter does not operate at 50% duty cycle, then the worst case capacitor RMS current  $I_{Cin}$  occurs where the duty cycle is closest to 50% and can be estimated using  $\Delta \vec{x}$  5.

$$I_{CIN} = I_{CHG} \times \sqrt{D \times (1 - D)}$$
 (5)

Low ESR ceramic capacitor such as X7R or X5R is preferred for input decoupling capacitor and should be placed to the drain of the high-side MOSFET and source of the low-side MOSFET as close as possible. Voltage rating of the capacitor must be higher than normal input voltage level. A rating of 25-V or higher capacitor is preferred for 15 V input voltage. Capacitance of 22-µF is suggested for typical of 3A charging current.

#### 10.2.2.4 Output Capacitor

Ensure that the output capacitance has enough ripple current rating to absorb the output switching ripple current. 公式 6 shows the output capacitor RMS current I<sub>COUT</sub> calculation.

$$I_{COUT} = \frac{I_{RIPPLE}}{2 \times \sqrt{3}} \approx 0.29 \times I_{RIPPLE}$$
(6)

The output capacitor voltage ripple can be calculated as follows:

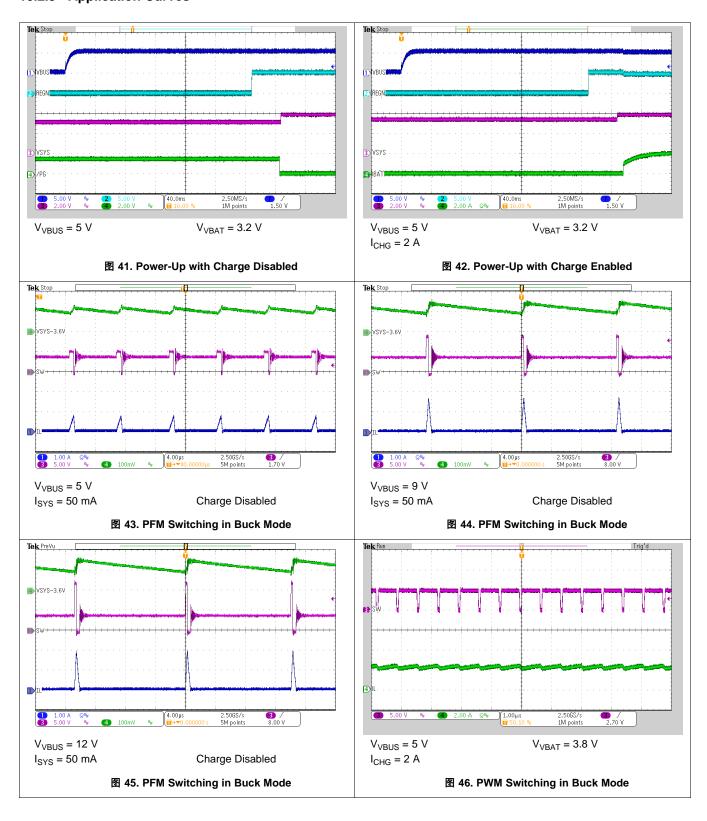
$$\Delta V_{O} = \frac{V_{OUT}}{8LCfs^{2}} \left( 1 - \frac{V_{OUT}}{V_{IN}} \right)$$
 (7)

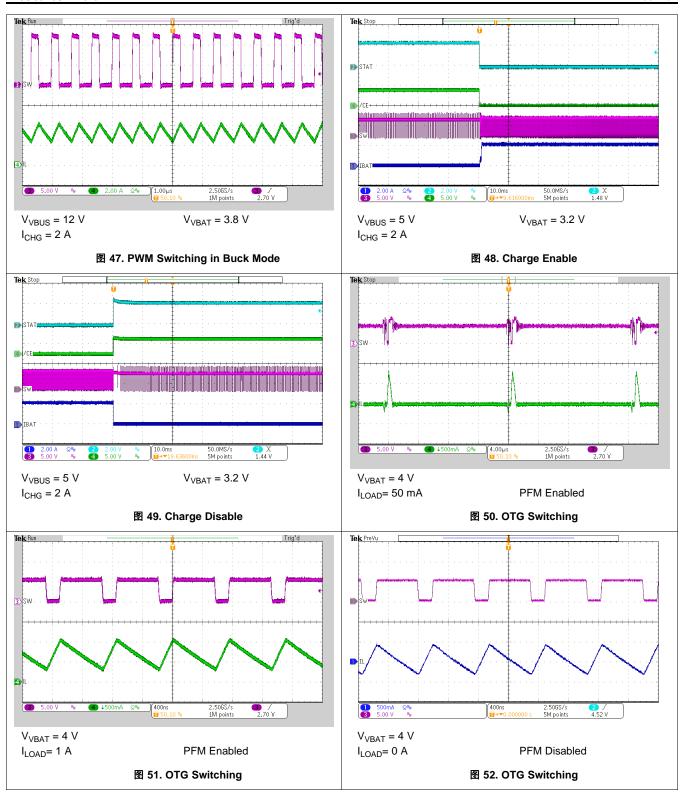
At certain input and output voltage and switching frequency, the voltage ripple can be reduced by increasing the output filter LC.

The charger device has internal loop compensation optimized for  $>20\mu F$  ceramic output capacitance. The preferred ceramic capacitor is 10V rating, X7R or X5R.

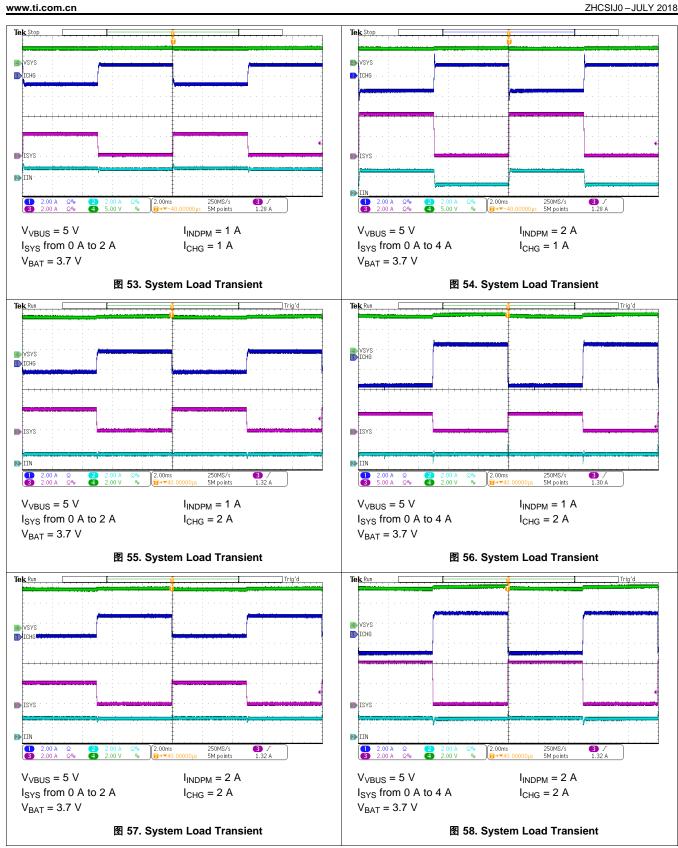


#### 10.2.3 Application Curves



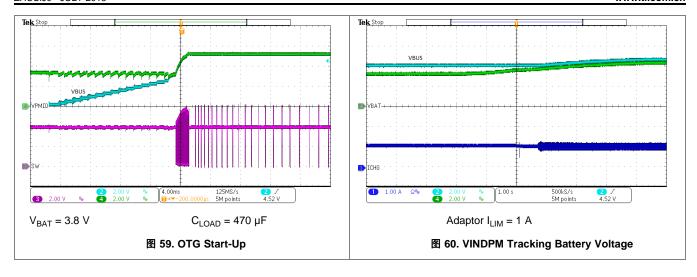






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## 11 Power Supply Recommendations

in order to provide an output voltage on SYS, the BQ25601D device requires a power supply between 3.9 V and 14.2 V input with at least 100-mA current rating connected to VBUS and a single-cell Li-lon battery with voltage > V<sub>BATUVLO</sub> connected to BAT. The source current rating needs to be at least 3 Å in order for the buck converter of the charger to provide maximum output power to SYS.

#### 12 Layout

#### 12.1 Layout Guidelines

The switching node rise and fall times should be minimized for minimum switching loss. Proper layout of the components to minimize high frequency current path loop (see 8 61) is important to prevent electrical and magnetic field radiation and high frequency resonant problems. Follow this specific order carefully to achieve the proper layout.

- 1. Place input capacitor as close as possible to PMID pin and GND pin connections and use shortest copper trace connection or GND plane.
- 2. Place inductor input pin to SW pin as close as possible. Minimize the copper area of this trace to lower electrical and magnetic field radiation but make the trace wide enough to carry the charging current. Do not use multiple layers in parallel for this connection. Minimize parasitic capacitance from this area to any other trace or plane.
- 3. Put output capacitor near to the inductor and the device. Ground connections need to be tied to the IC ground with a short copper trace connection or GND plane.
- 4. Route analog ground separately from power ground. Connect analog ground and connect power ground separately. Connect analog ground and power ground together using thermal pad as the single ground connection point. Or using a  $0-\Omega$  resistor to tie analog ground to power ground.
- 5. Use single ground connection to tie charger power ground to charger analog ground. Just beneath the device. Use ground copper pour but avoid power pins to reduce inductive and capacitive noise coupling.
- 6. Place decoupling capacitors next to the IC pins and make trace connection as short as possible.
- 7. It is critical that the exposed thermal pad on the backside of the device package be soldered to the PCB ground. Ensure that there are sufficient thermal vias directly under the IC, connecting to the ground plane on the other layers.
- 8. Ensure that the number and sizes of vias allow enough copper for a given current path.

See the EVM user's guide SLUUBL4 for the recommended component placement with trace and via locations. For the VQFN information, refer to SCBA017 and SLUA271.

#### 12.2 Layout Example

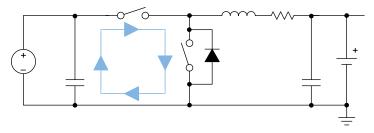


图 61. High Frequency Current Path



# Layout Example (接下页)

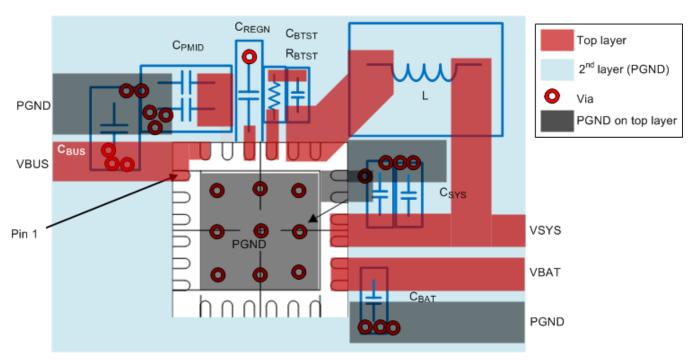


图 62. Layout Example

# TEXAS INSTRUMENTS

#### 13 器件和文档支持

#### 13.1 器件支持

#### 13.1.1 开发支持

#### **13.1.1.1** 使用 WEBENCH® 工具创建定制设计

请单击此处,使用 BQ25601D 器件并借助 WEBENCH® 电源设计器创建定制设计方案。

- 1. 首先输入输入电压  $(V_{IN})$ 、输出电压  $(V_{OUT})$  和输出电流  $(I_{OUT})$  要求。
- 2. 使用优化器拨盘优化该设计的关键参数,如效率、尺寸和成本。
- 3. 将生成的设计与德州仪器 (TI) 的其他可行的解决方案进行比较。

WEBENCH 电源设计器可提供定制原理图以及罗列实时价格和组件供货情况的物料清单。

在多数情况下,可执行以下操作:

- 运行电气仿真,观察重要波形以及电路性能
- 运行热性能仿真,了解电路板热性能
- 将定制原理图和布局方案以常用 CAD 格式导出
- 打印设计方案的 PDF 报告并与同事共享

有关 WEBENCH 工具的详细信息,请访问 www.ti.com.cn/WEBENCH。

#### 13.2 文档支持

#### 13.2.1 相关文档

请参阅如下相关文档:

• EVM 用户指南 (SLUUBL4)

#### 13.3 接收文档更新通知

要接收文档更新通知,请导航至 Tl.com.cn 上的器件产品文件夹。单击右上角的通知我 进行注册,即可每周接收产品信息更改摘要。有关更改的详细信息,请查看任何已修订文档中包含的修订历史记录。

#### 13.4 社区资源

下列链接提供到 TI 社区资源的连接。链接的内容由各个分销商"按照原样"提供。这些内容并不构成 TI 技术规范,并且不一定反映 TI 的观点;请参阅 TI 的 《使用条款》。

TI E2E™ 在线社区 TI 的工程师对工程师 (E2E) 社区。此社区的创建目的在于促进工程师之间的协作。在 e2e.ti.com 中,您可以咨询问题、分享知识、拓展思路并与同行工程师一道帮助解决问题。

设计支持 TI 参考设计支持 可帮助您快速查找有帮助的 E2E 论坛、设计支持工具以及技术支持的联系信息。

#### 13.5 商标

E2E is a trademark of Texas Instruments.

WEBENCH is a registered trademark of Texas Instruments.

All other trademarks are the property of their respective owners.

#### 13.6 静电放电警告



这些装置包含有限的内置 ESD 保护。 存储或装卸时,应将导线一起截短或将装置放置于导电泡棉中,以防止 MOS 门极遭受静电损伤。

#### 13.7 术语表

SLYZ022 — TI 术语表。

这份术语表列出并解释术语、缩写和定义。





# 14 机械、封装和可订购信息

以下页面包含机械、封装和可订购信息。这些信息是指定器件的最新可用数据。数据如有变更,恕不另行通知,且 不会对此文档进行修订。如需获取此产品说明书的浏览器版本,请查阅左侧的导航栏。



### PACKAGE OPTION ADDENDUM

10-Dec-2020

#### **PACKAGING INFORMATION**

www.ti.com

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
BQ25601DRTWR	ACTIVE	WQFN	RTW	24	3000	RoHS & Green	. ,	Level-2-260C-1 YEAR	-40 to 85	BQ 25601D	Samples
BQ25601DRTWT	ACTIVE	WQFN	RTW	24	250	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	BQ 25601D	Samples

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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10-Dec-2020

PACKAGE MATERIALS INFORMATION

www.ti.com 25-Jul-2018

### TAPE AND REEL INFORMATION





	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

#### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

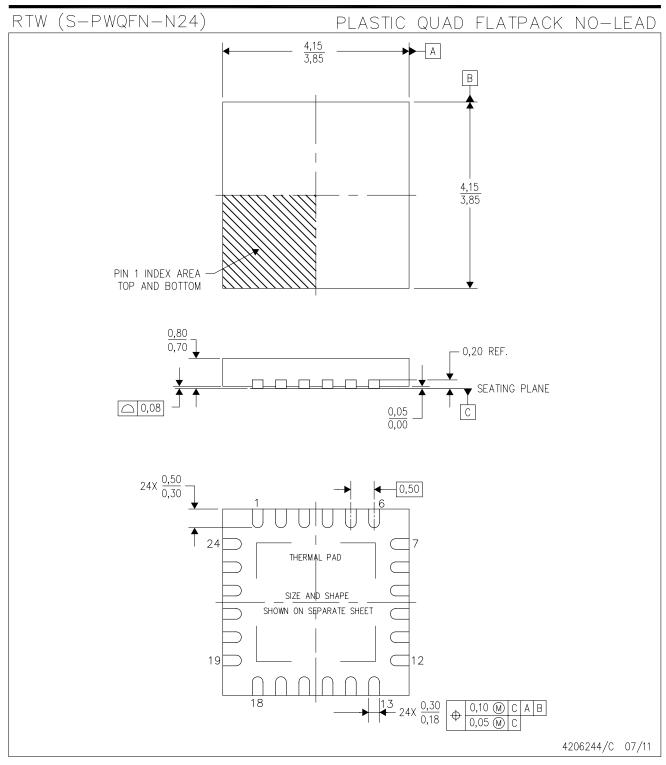
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
BQ25601DRTWR	WQFN	RTW	24	3000	330.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2
BQ25601DRTWT	WQFN	RTW	24	250	180.0	12.4	4.25	4.25	1.15	8.0	12.0	Q2

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#### \*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)	
BQ25601DRTWR	WQFN	RTW	24	3000	367.0	367.0	35.0	
BQ25601DRTWT	WQFN	RTW	24	250	210.0	185.0	35.0	



- NOTES: A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
  - B. This drawing is subject to change without notice.
  - C. Quad Flatpack, No-Leads (QFN) package configuration.
  - D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
  - E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
  - F. Falls within JEDEC MO-220.



# RTW (S-PWQFN-N24)

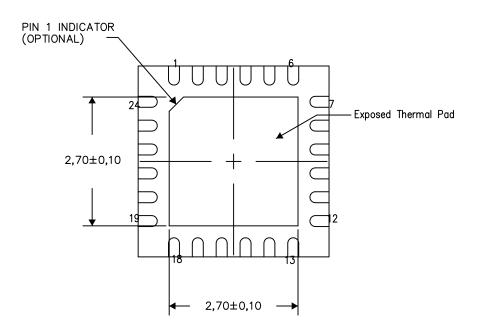
# PLASTIC QUAD FLATPACK NO-LEAD

#### THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No—Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View
Exposed Thermal Pad Dimensions

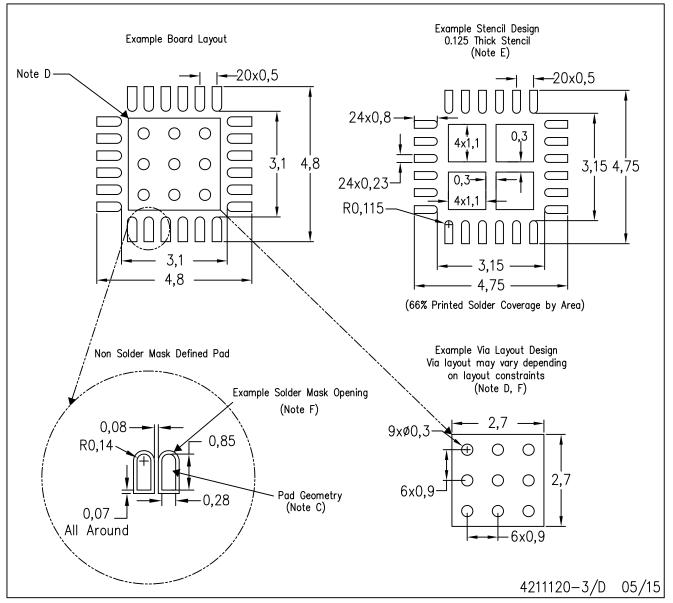
4206249-5/P 05/15

NOTES: A. All linear dimensions are in millimeters



# RTW (S-PWQFN-N24)

## PLASTIC QUAD FLATPACK NO-LEAD



NOTES:

- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat—Pack Packages, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <a href="http://www.ti.com">www.ti.com</a>.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
- F. Customers should contact their board fabrication site for recommended solder mask tolerances and via tenting recommendations for vias placed in the thermal pad.



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